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FIG. 1A

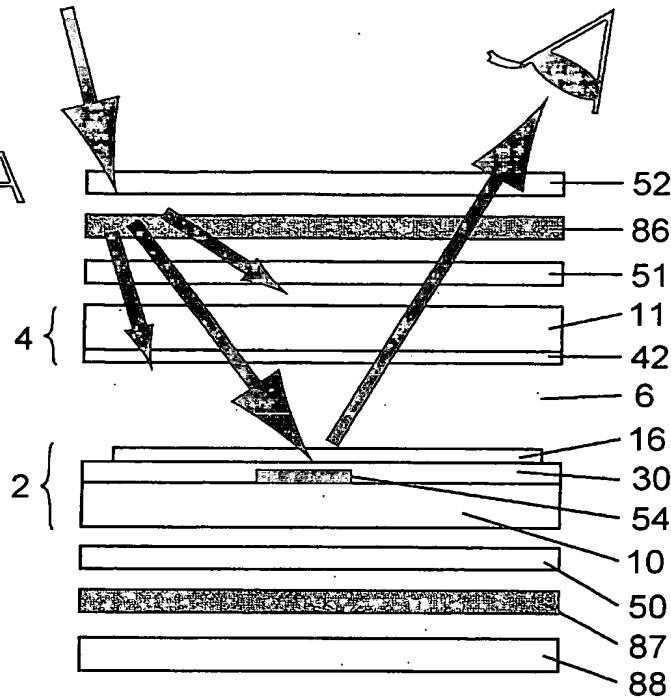
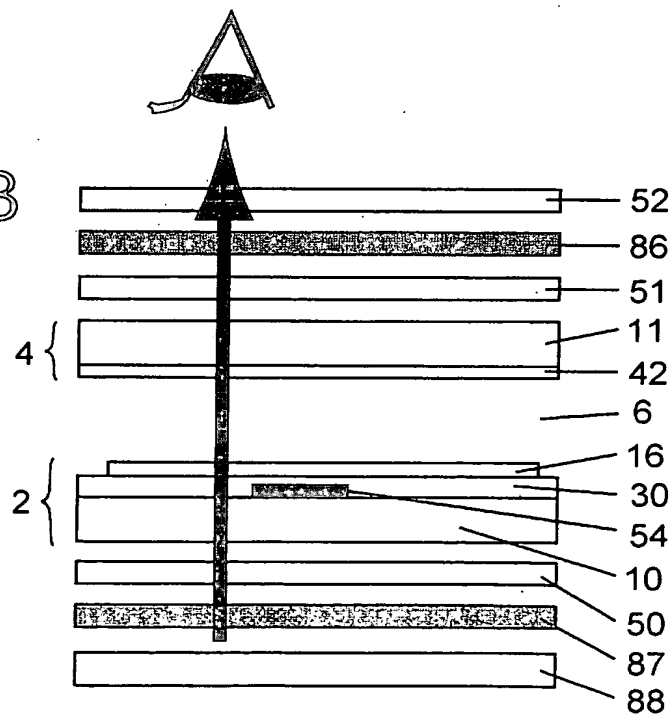
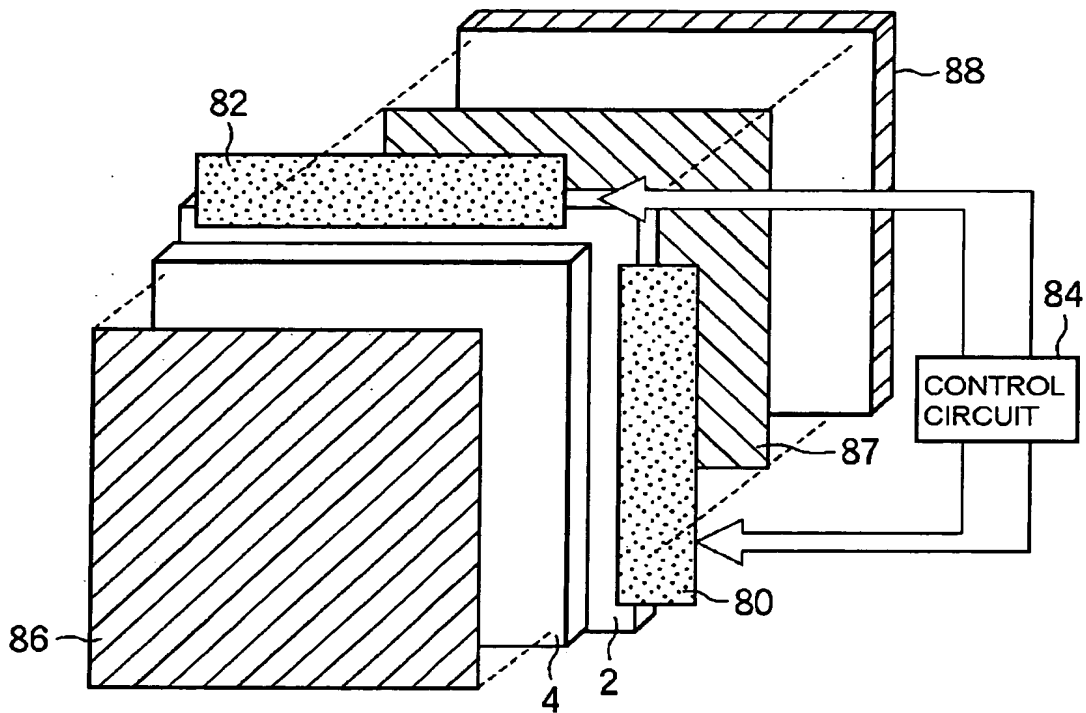


FIG. 1B



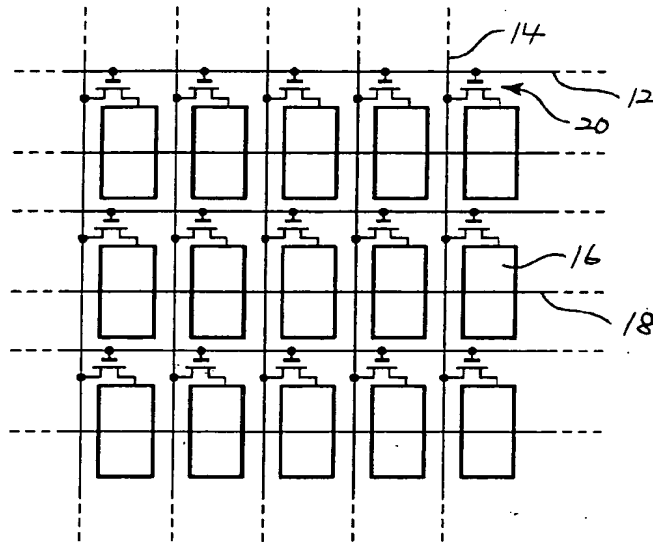
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FIG. 2



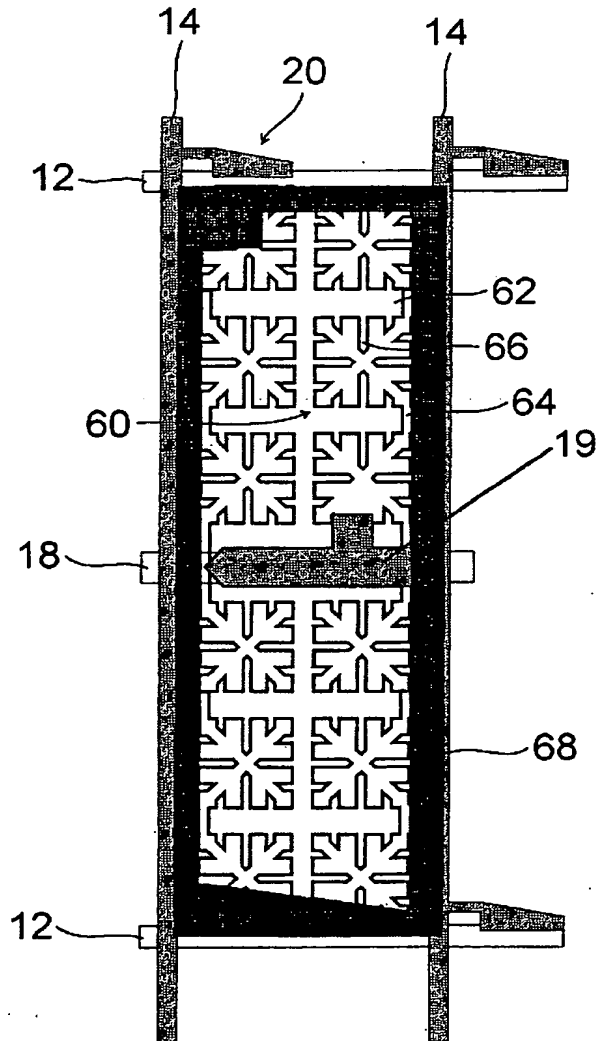
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FIG.3



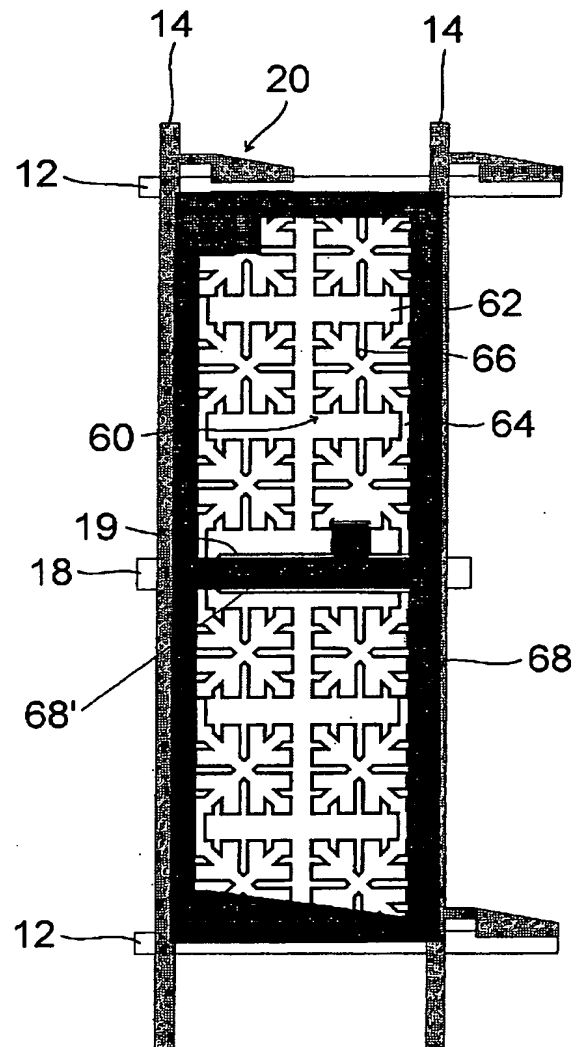
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FIG.4



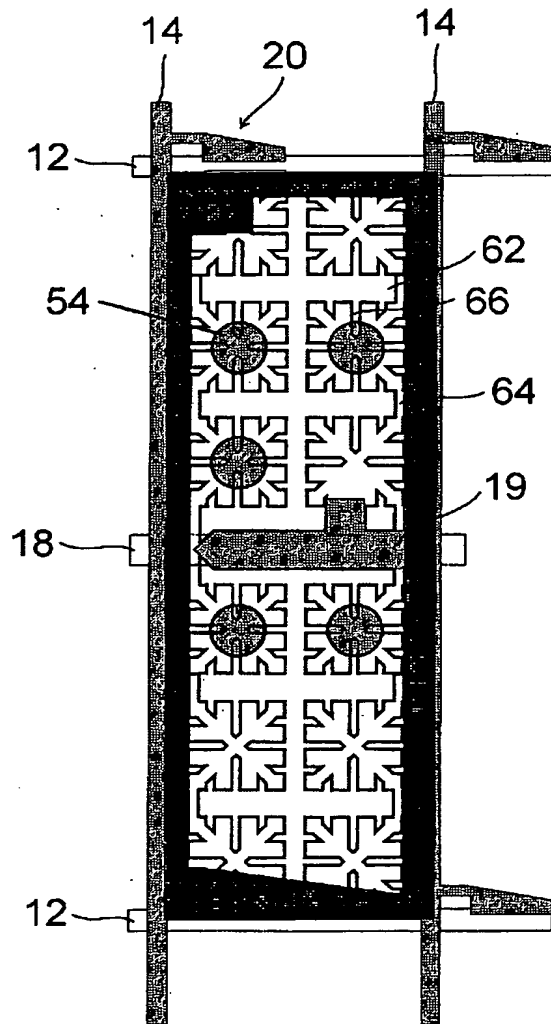
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FIG.5



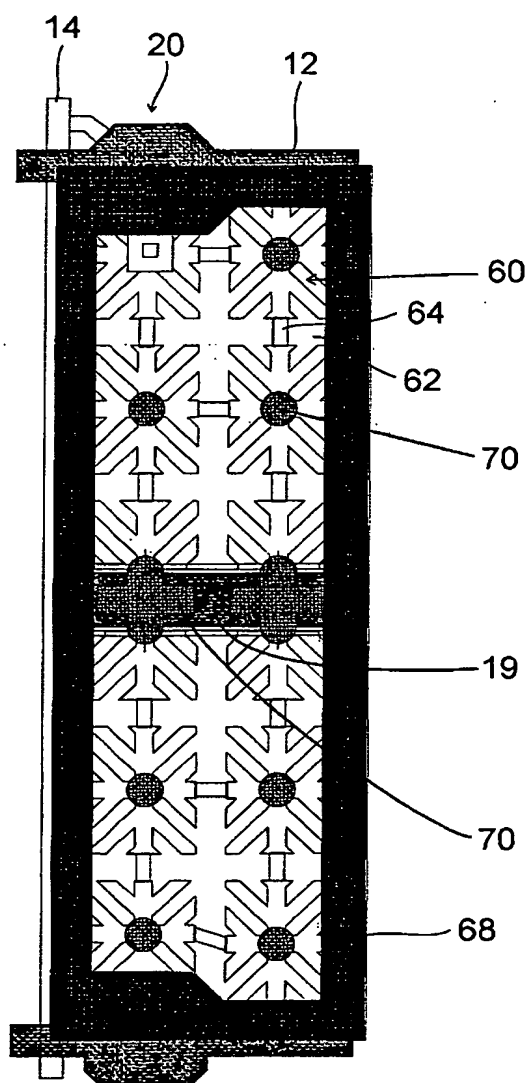
6/60

FIG.6



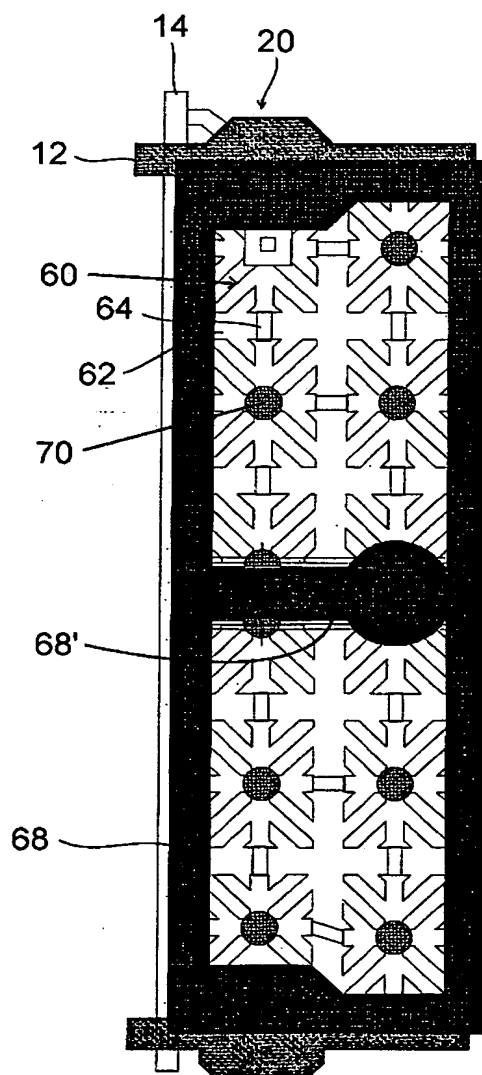
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FIG. 7



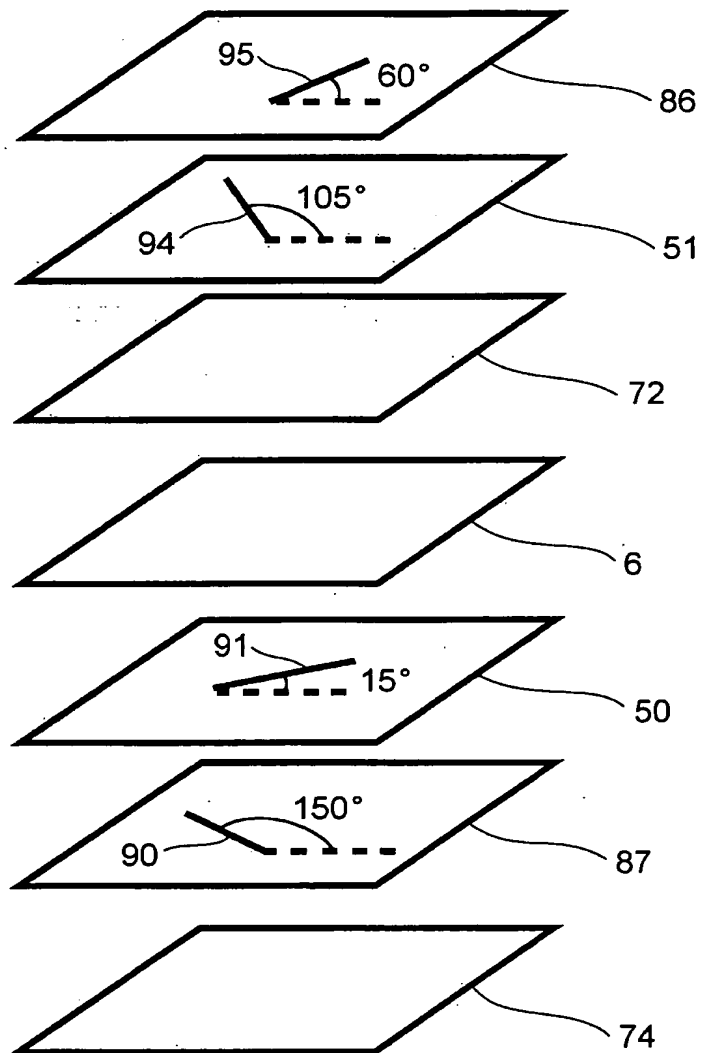
8/60

FIG. 8



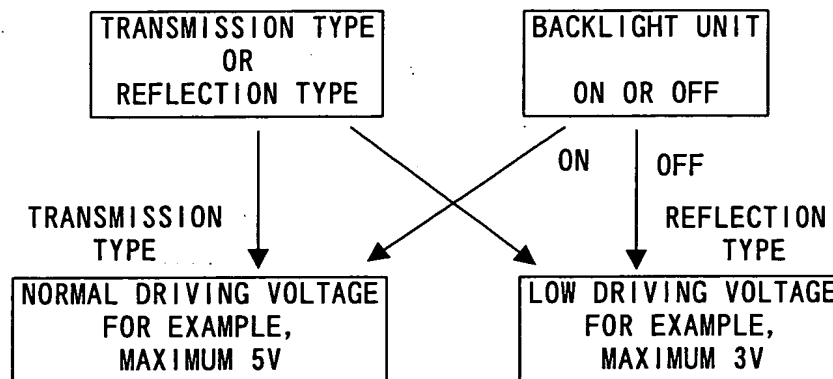
9/60

FIG. 9



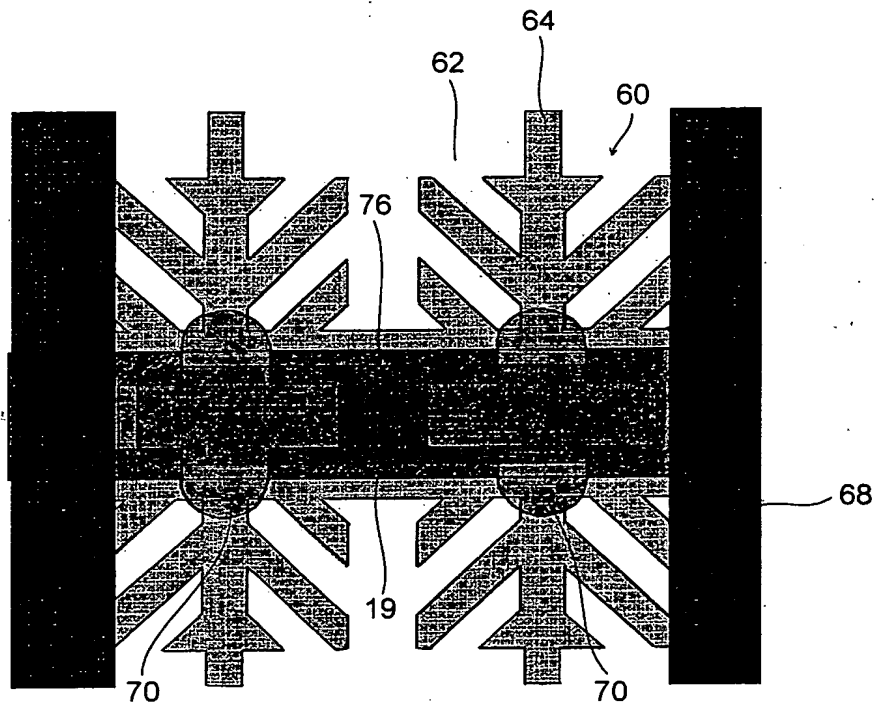
10/60

FIG.10



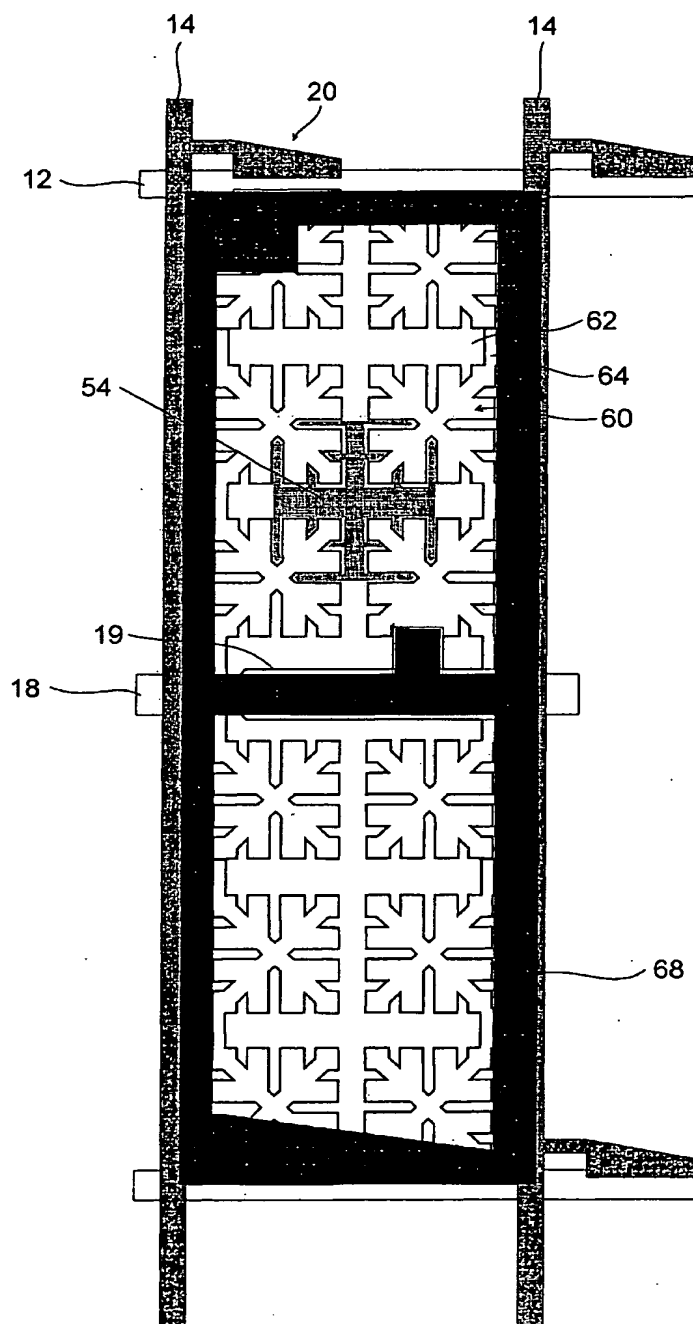
11/60

FIG. 11



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FIG.12



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FIG.13

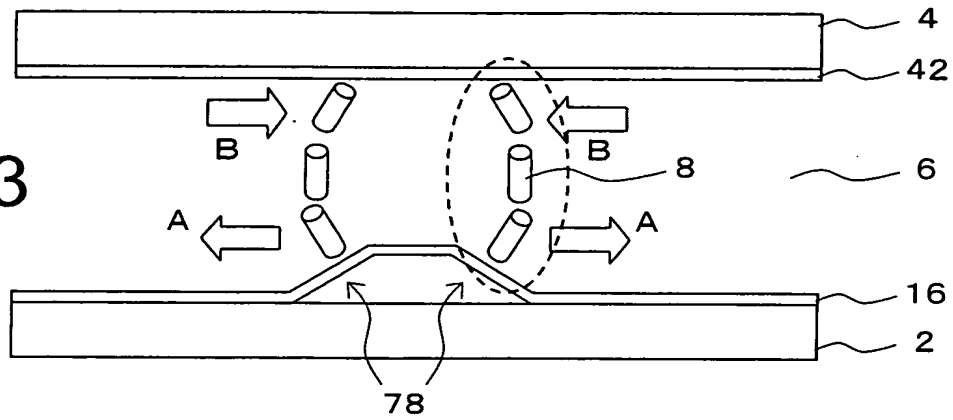


FIG.14

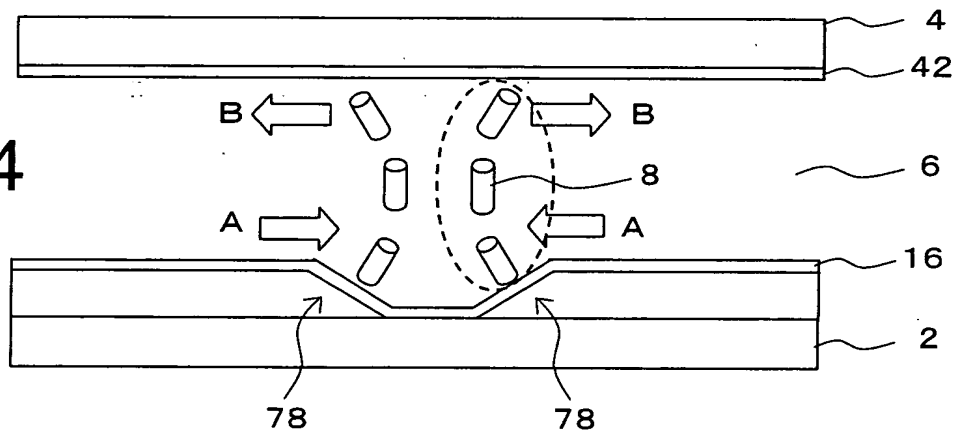
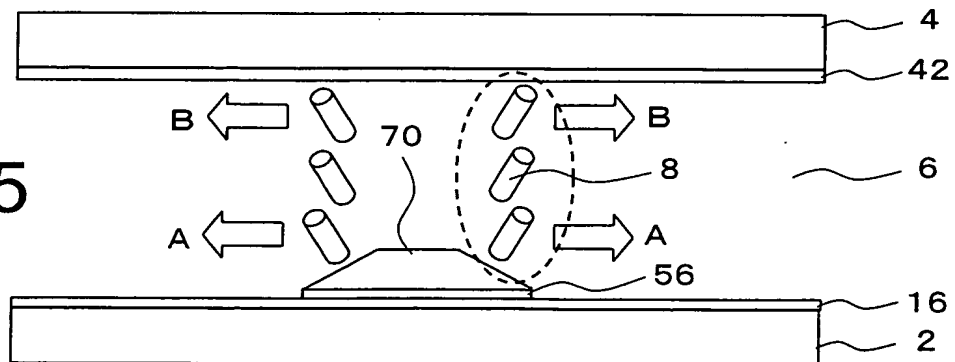


FIG.15



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FIG.16

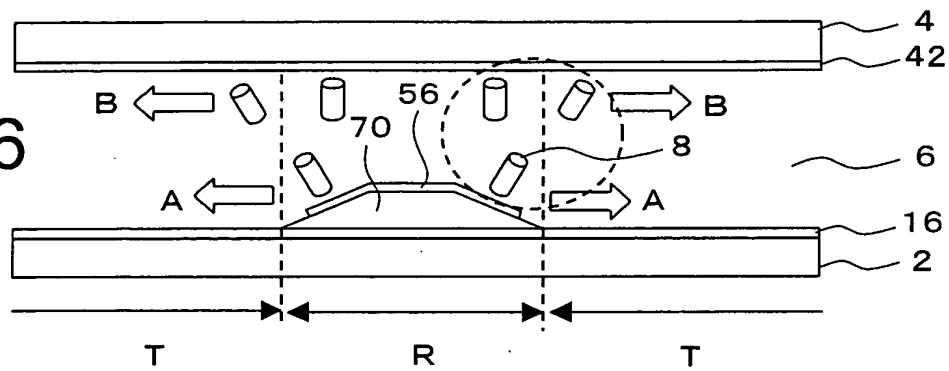


FIG.17

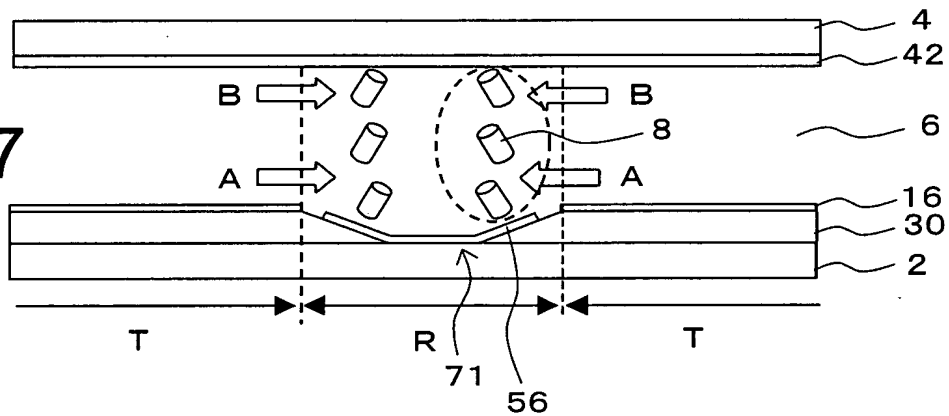
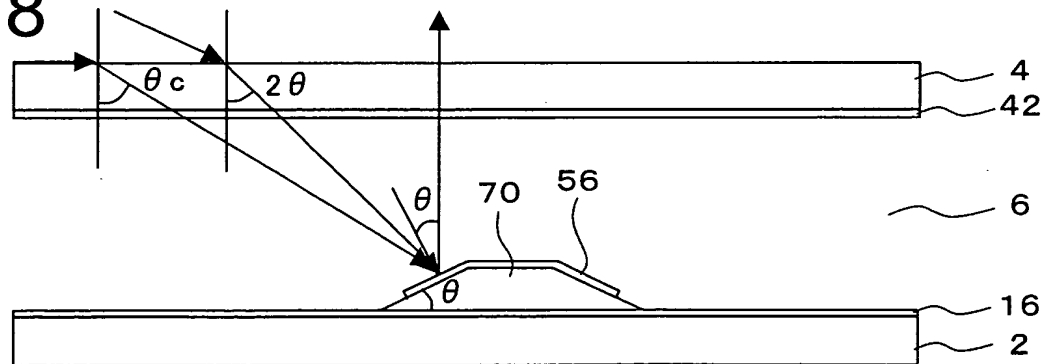


FIG.18



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FIG.19

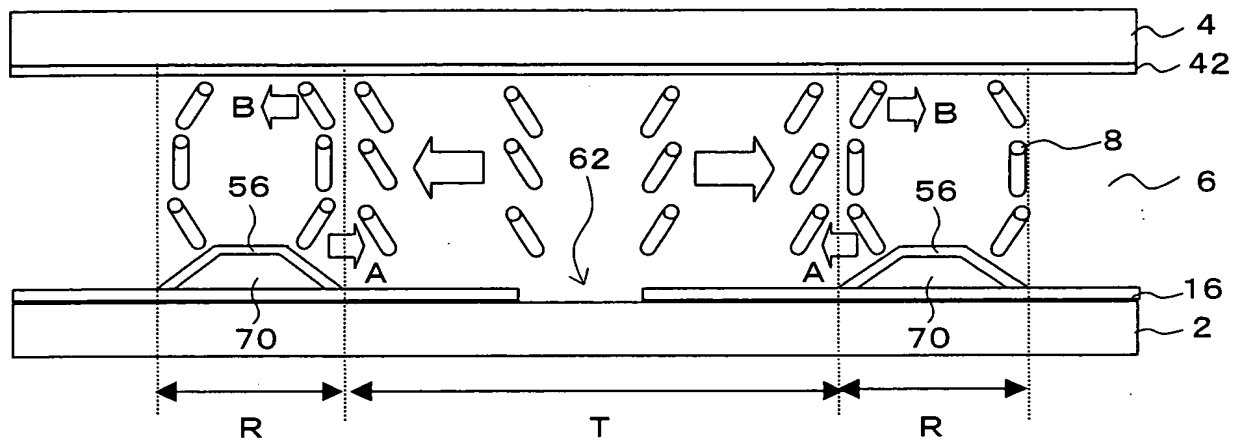
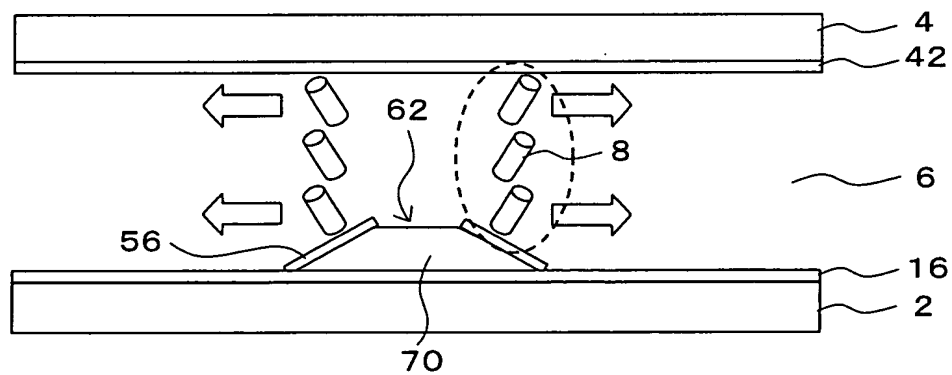


FIG.20



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FIG.21

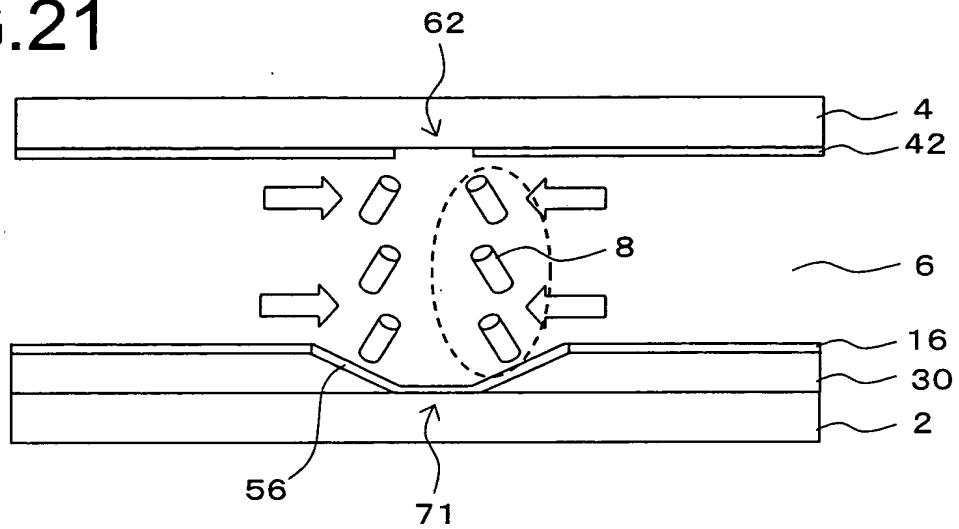


FIG.22

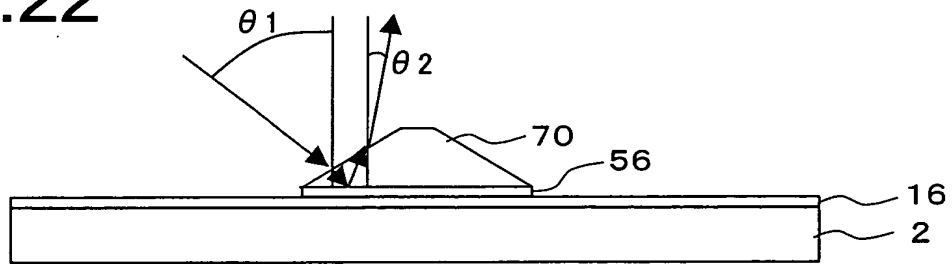
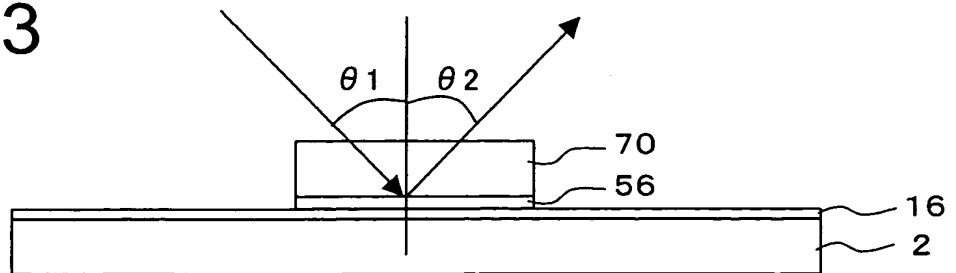


FIG.23



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FIG.24

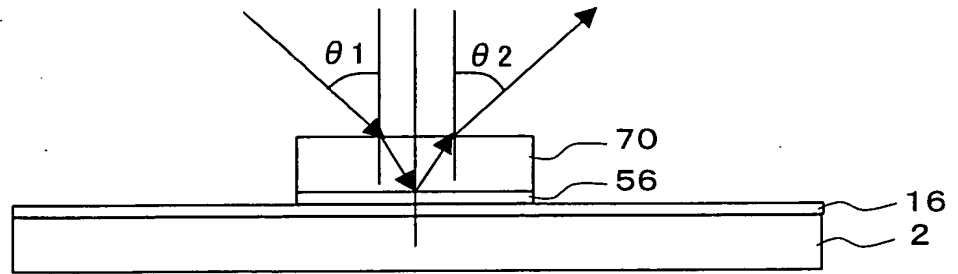
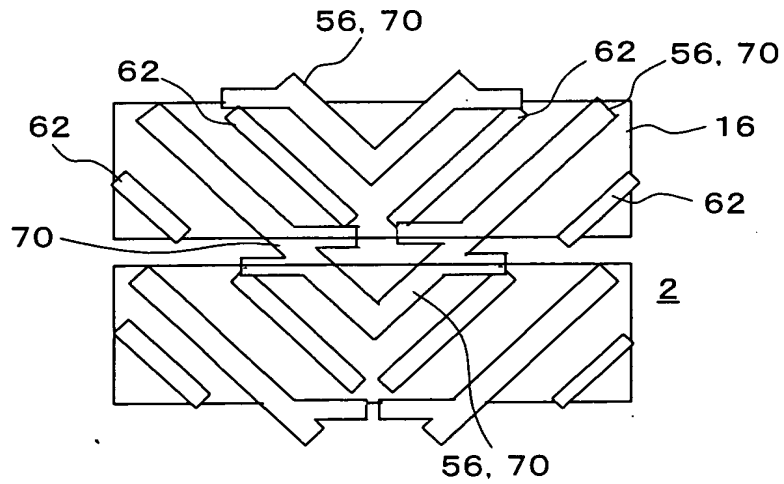


FIG.25



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FIG.26

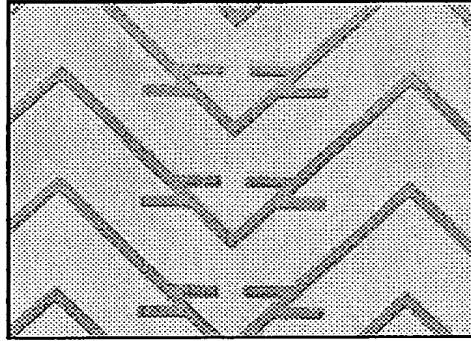


FIG.27

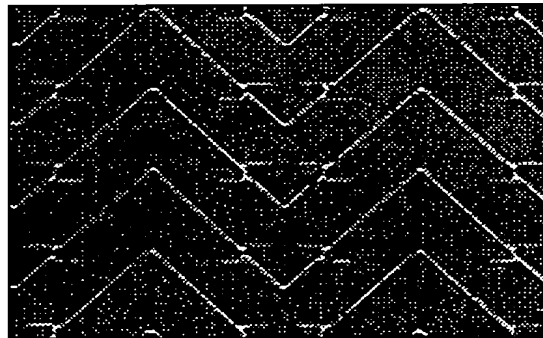
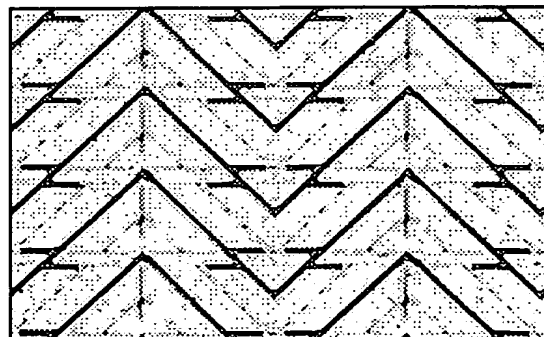


FIG.28



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FIG.29

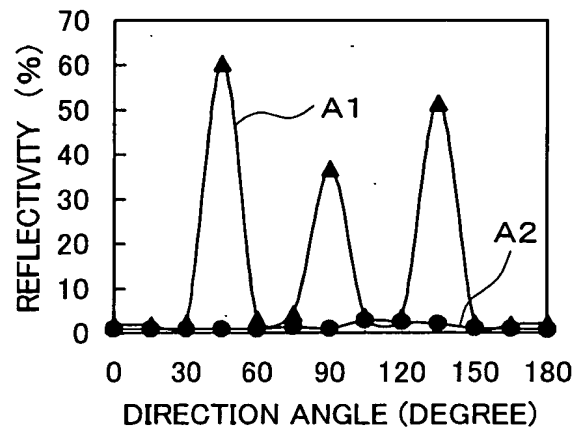
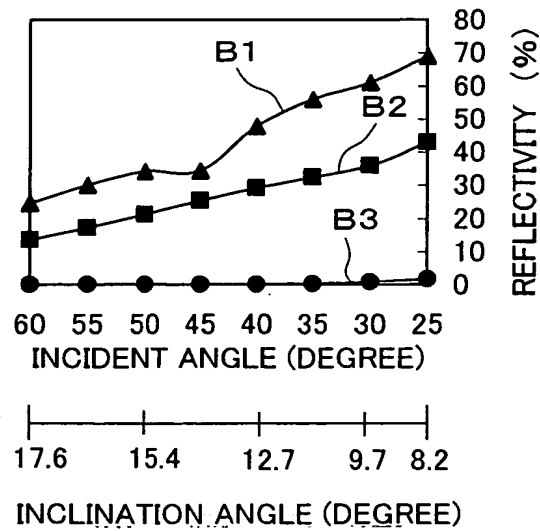
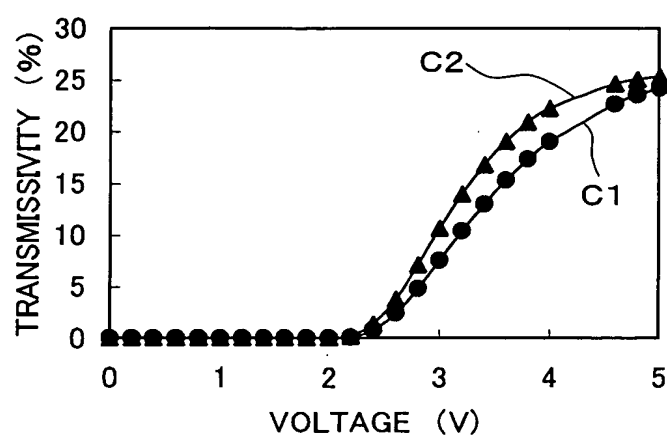


FIG.30



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FIG.31



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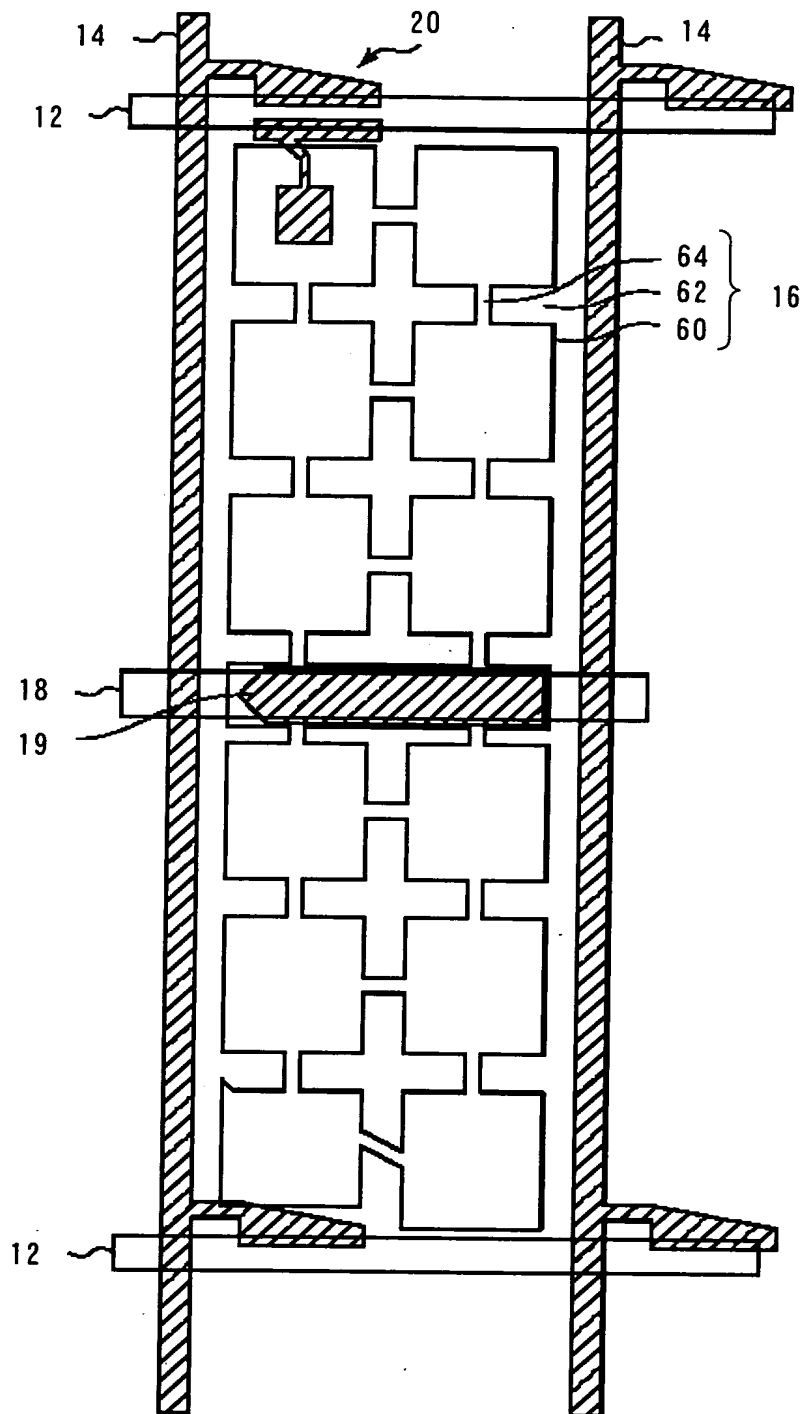


FIG.32

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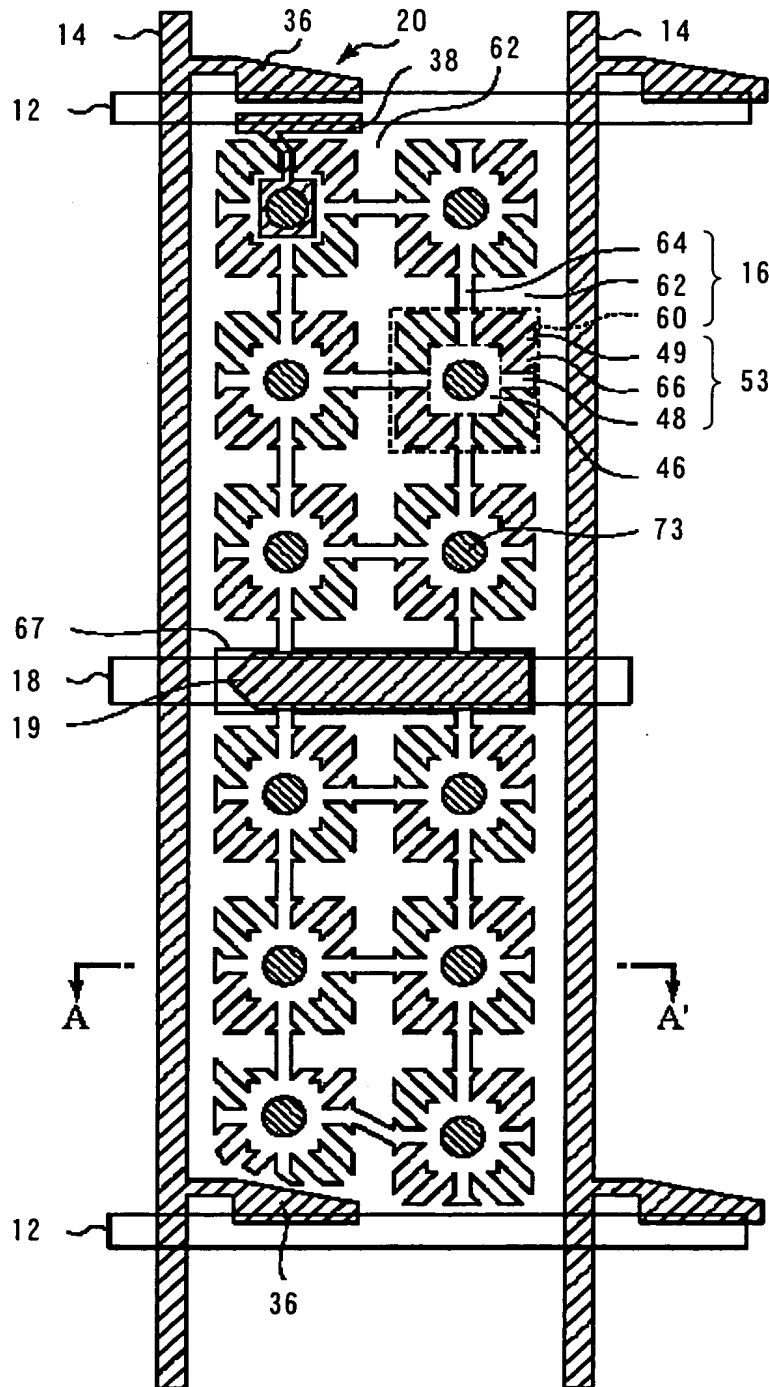


FIG.33

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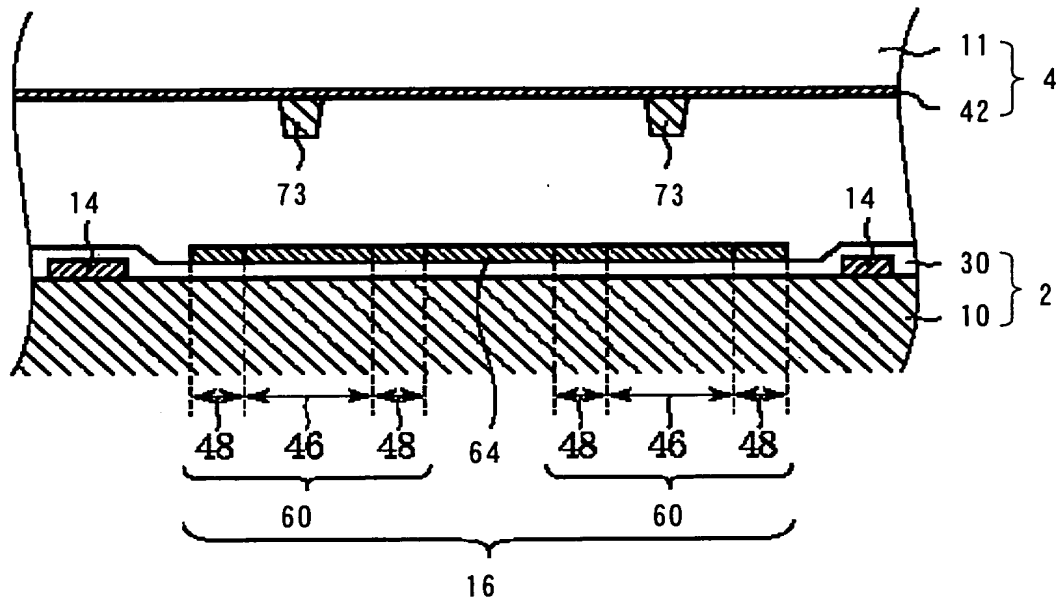


FIG.34

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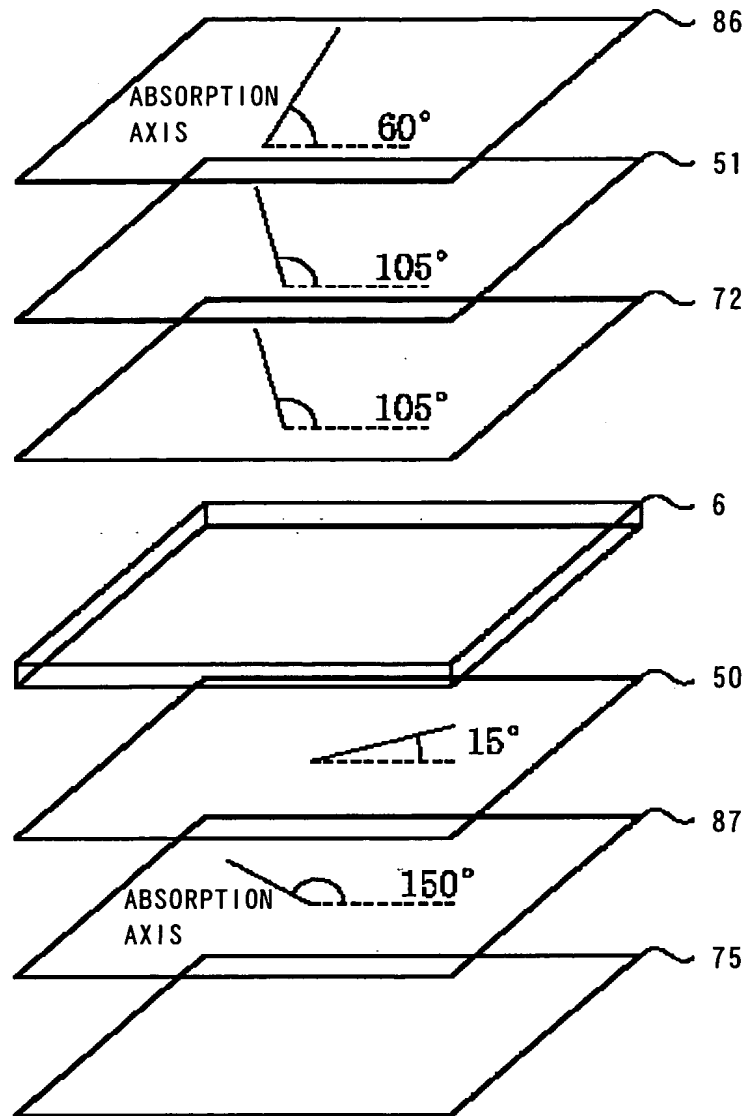


FIG.35

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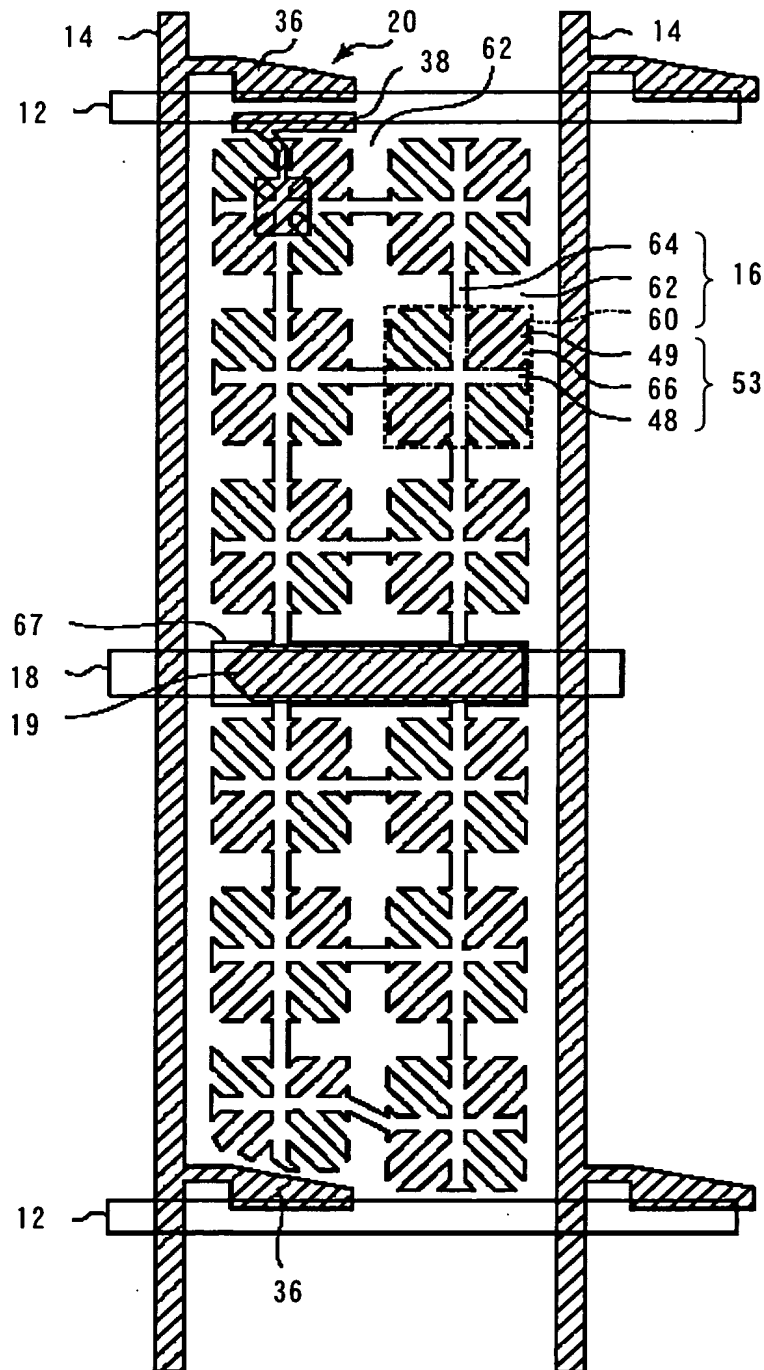


FIG.36

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FIG.37

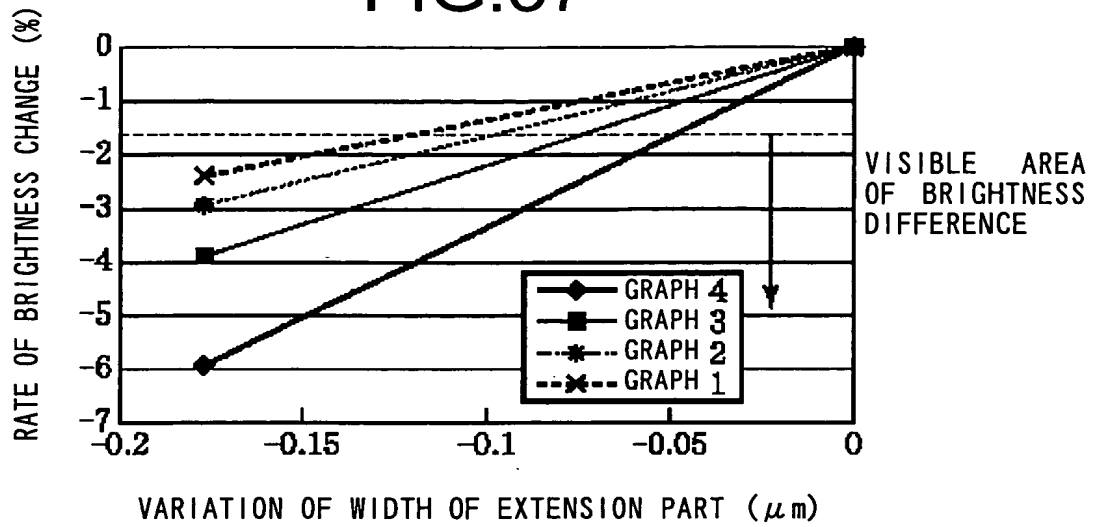


FIG.38A



FIG.38B



FIG.38C



FIG.38D



This cross-sectional view shows a semiconductor device with two active regions. The substrate is labeled 10. A layer 12 is formed on the substrate. A layer 22 is formed on layer 12. A layer 23 is formed on layer 22. A layer 24 is formed on layer 23. A layer 25 is formed on layer 24. A layer 36 is formed on layer 25. A layer 38 is formed on layer 36. The active regions are labeled 20. The regions between the active regions are labeled 21.

This cross-sectional view shows a semiconductor device with a central channel region (20) and side contact regions (25). The device is built on a substrate (10) with a base layer (12). The channel region (20) is defined by a central layer (26) and side layers (24). The side contact regions (25) are defined by a central layer (27) and side layers (24). The device is covered by a top layer (36) with a central opening (38). The side contact regions (25) are also covered by a top layer (36) with a central opening (38). The device is labeled 40B.

40C

This cross-sectional view shows a semiconductor device 40C. It features a substrate 10 with a base layer 12. A central layer 16 is flanked by two side regions 20. Each side region 20 contains a stack of layers 22, 23, and 25. A conductive layer 24 is positioned on top of the side regions, with a contact pad 36 and a contact 38. A layer 26 is located between the central layer 16 and the side regions 20.

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FIG.41A

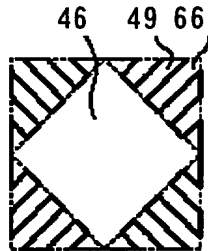


FIG.41B

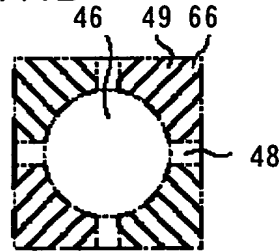


FIG.41C

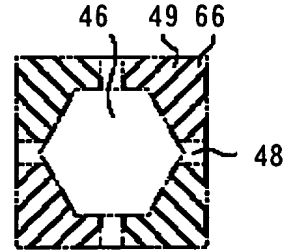


FIG.41D

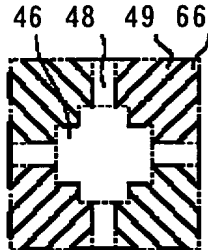


FIG.41E

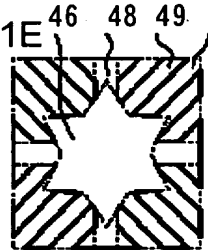


FIG.41F

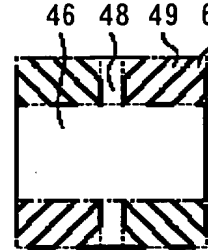


FIG.41G

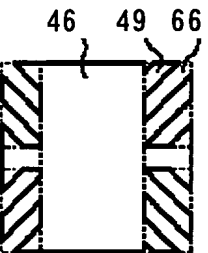


FIG.41H

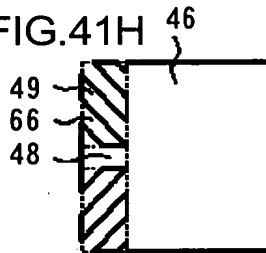


FIG.41I

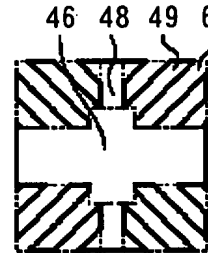


FIG.41J

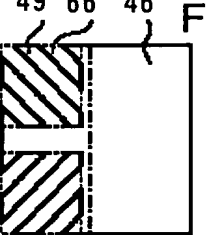


FIG.41K

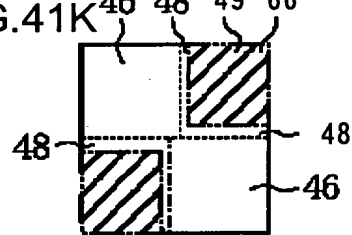


FIG.41L

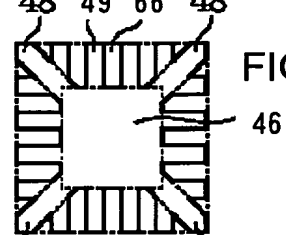


FIG.41M

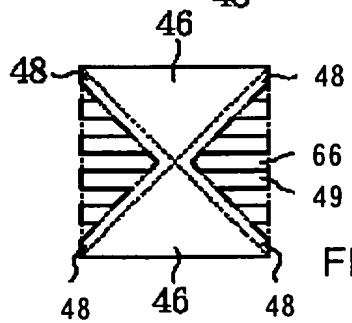
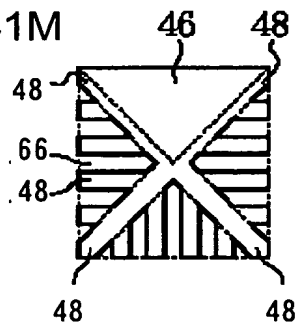
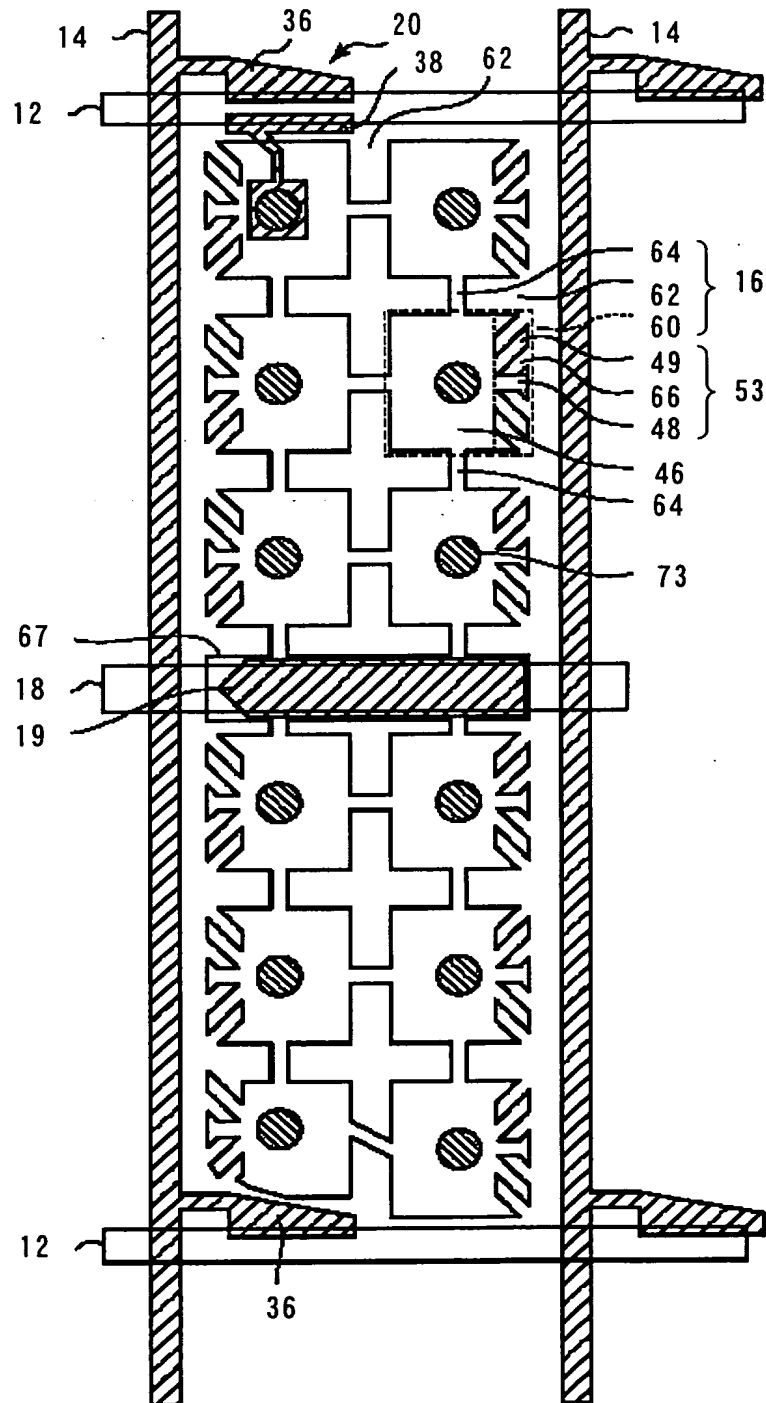


FIG.41N

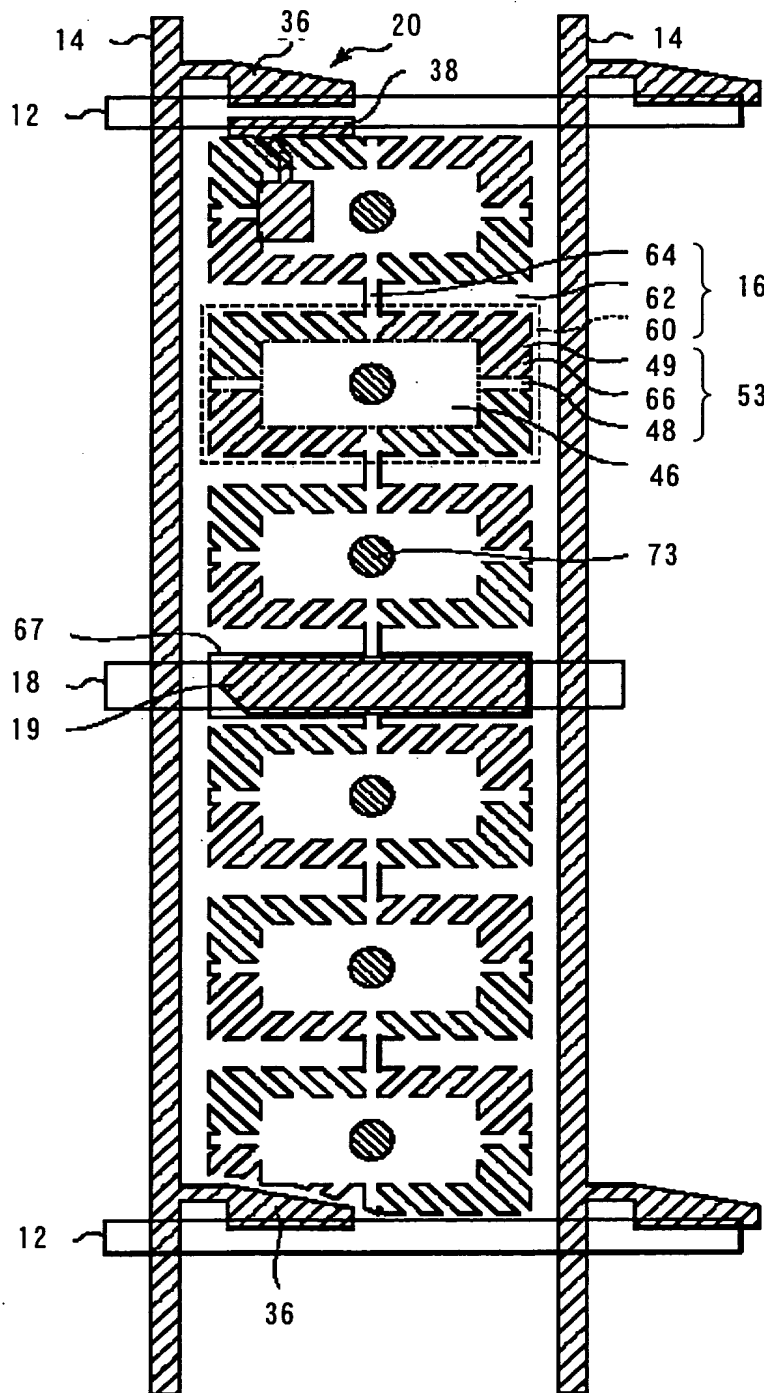
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FIG.42



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FIG.43



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FIG.44A

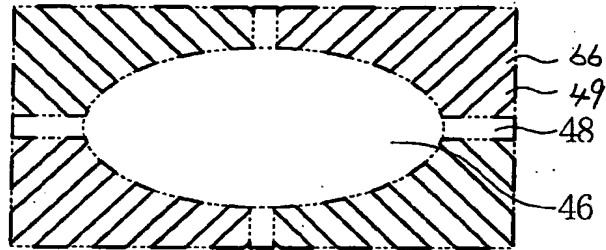


FIG.44B

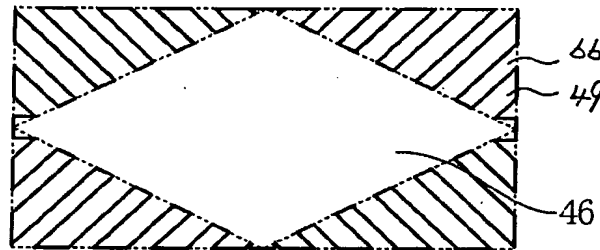
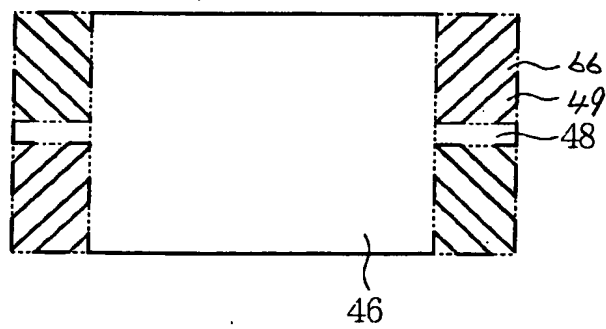
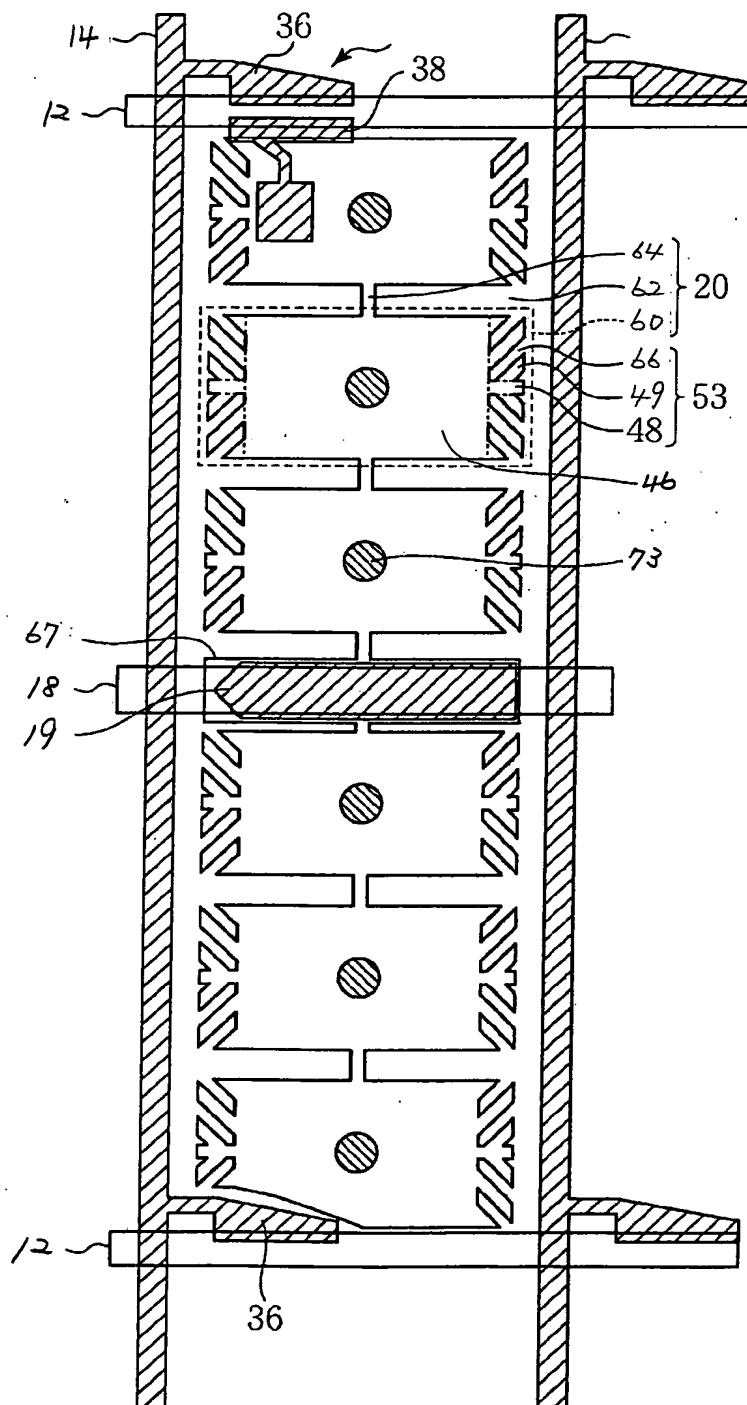


FIG.44C



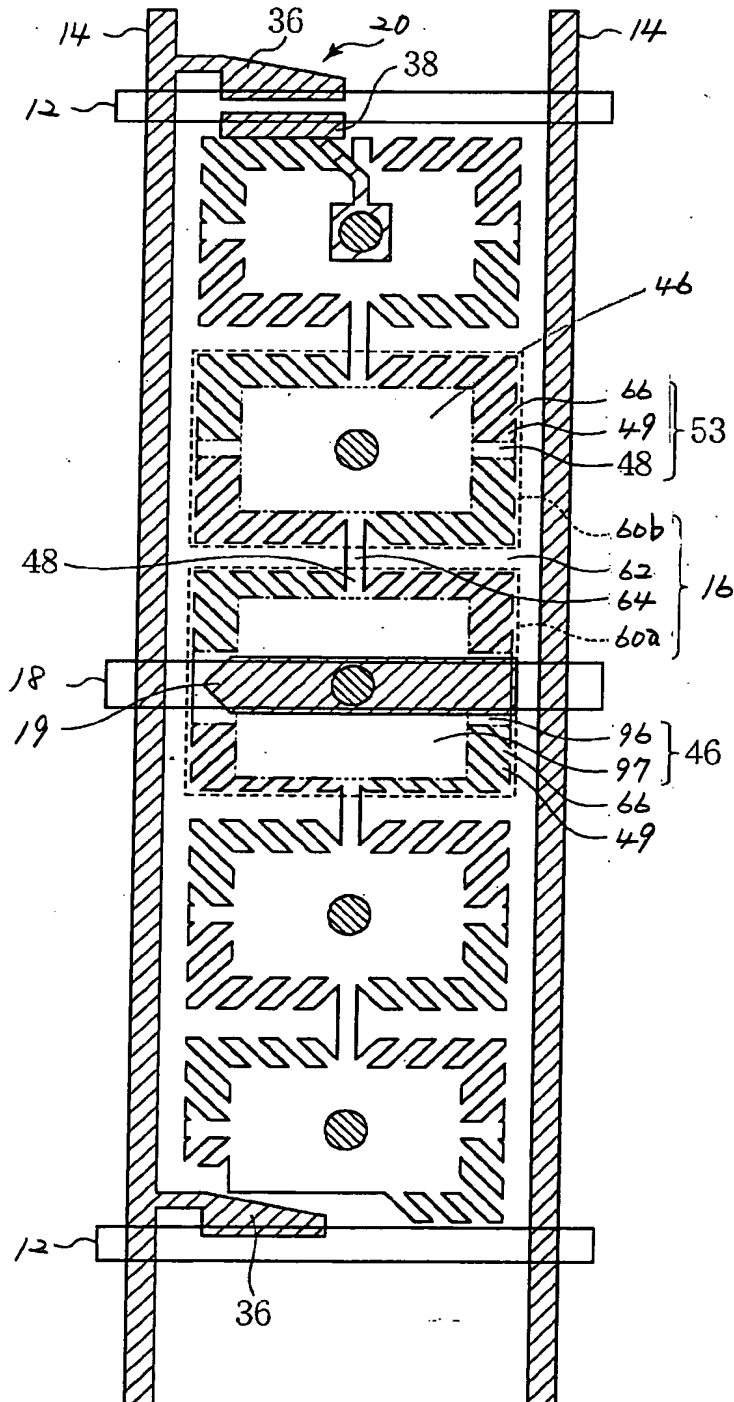
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FIG. 45



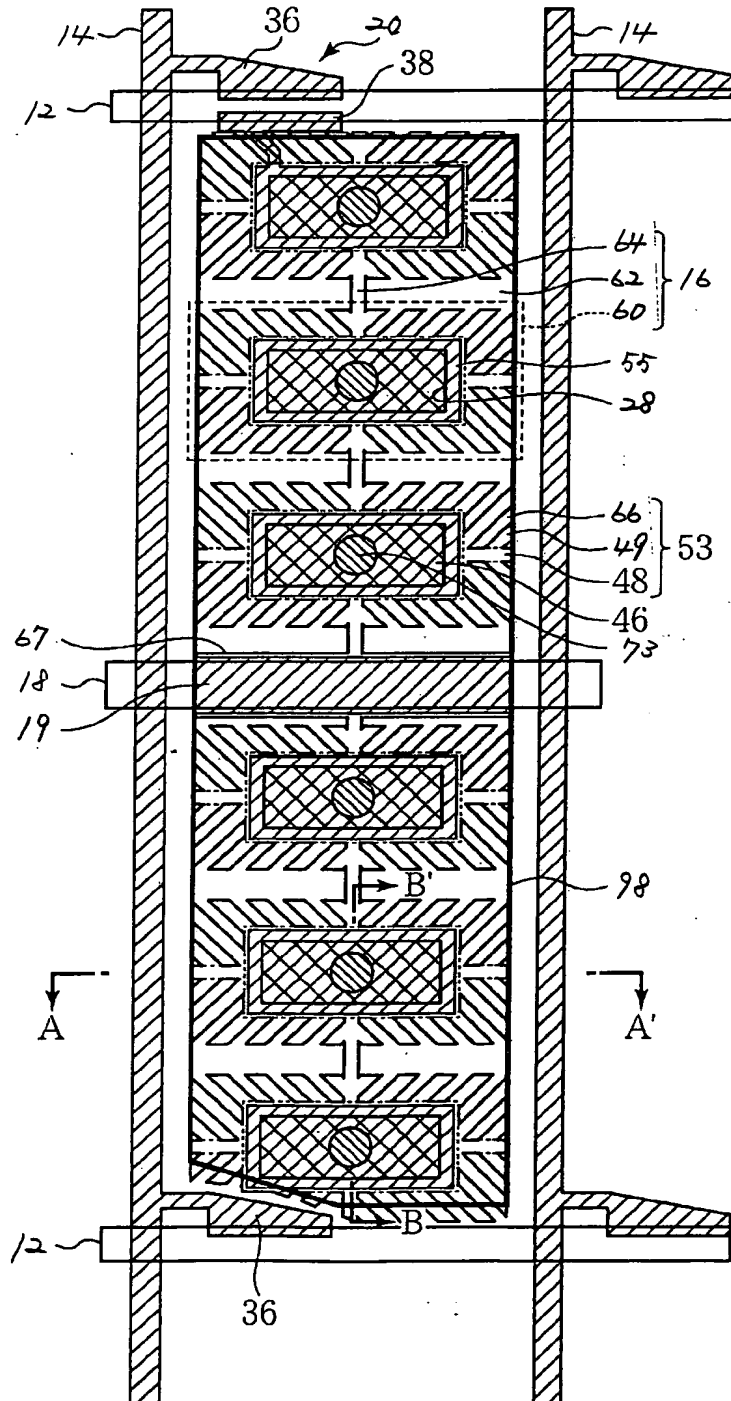
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FIG. 46



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FIG. 47



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FIG. 48A

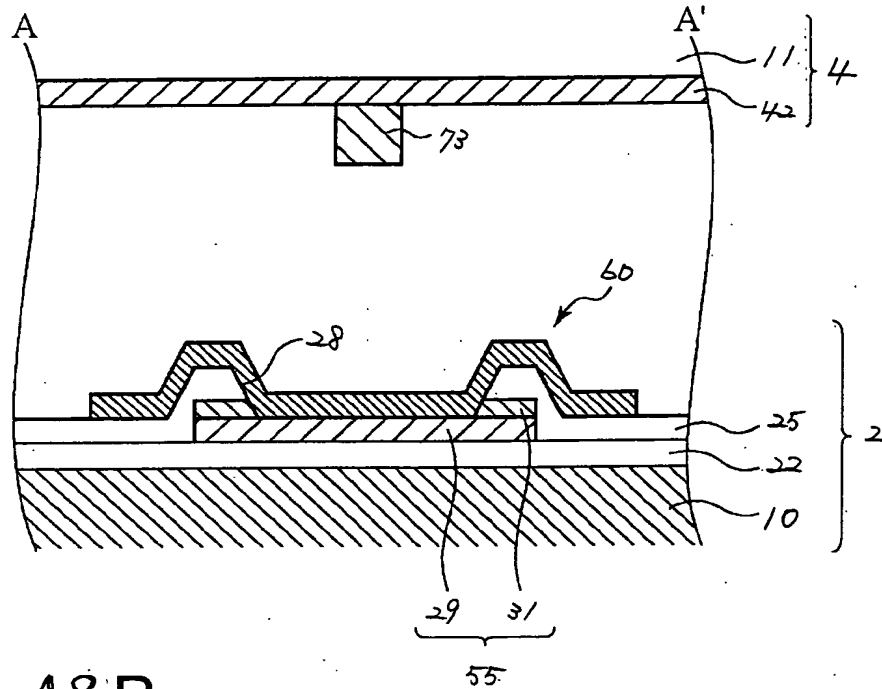
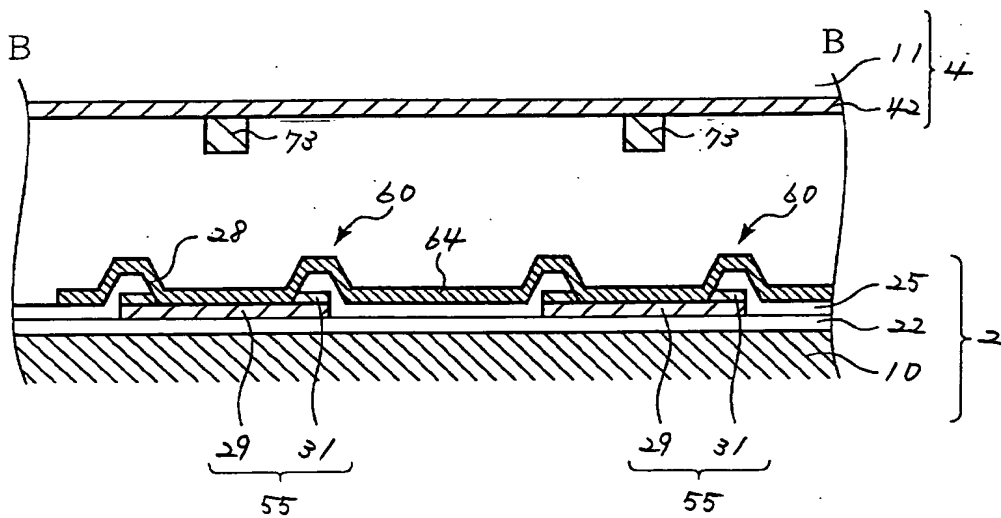
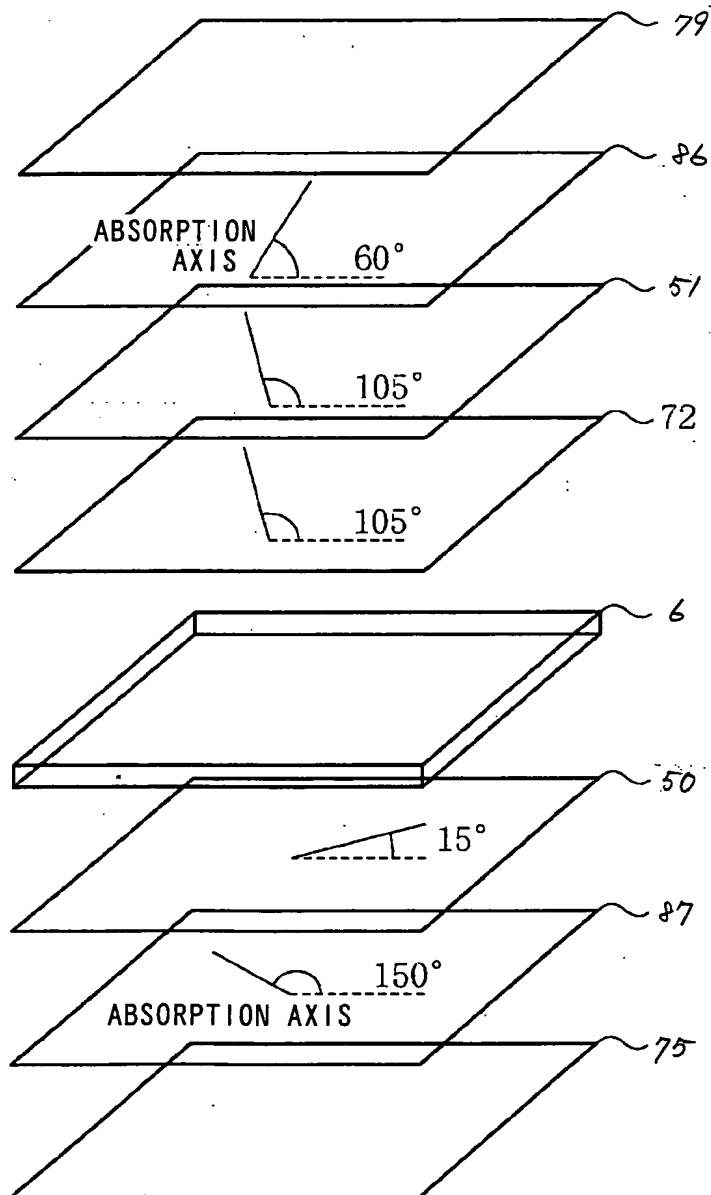


FIG. 48 B



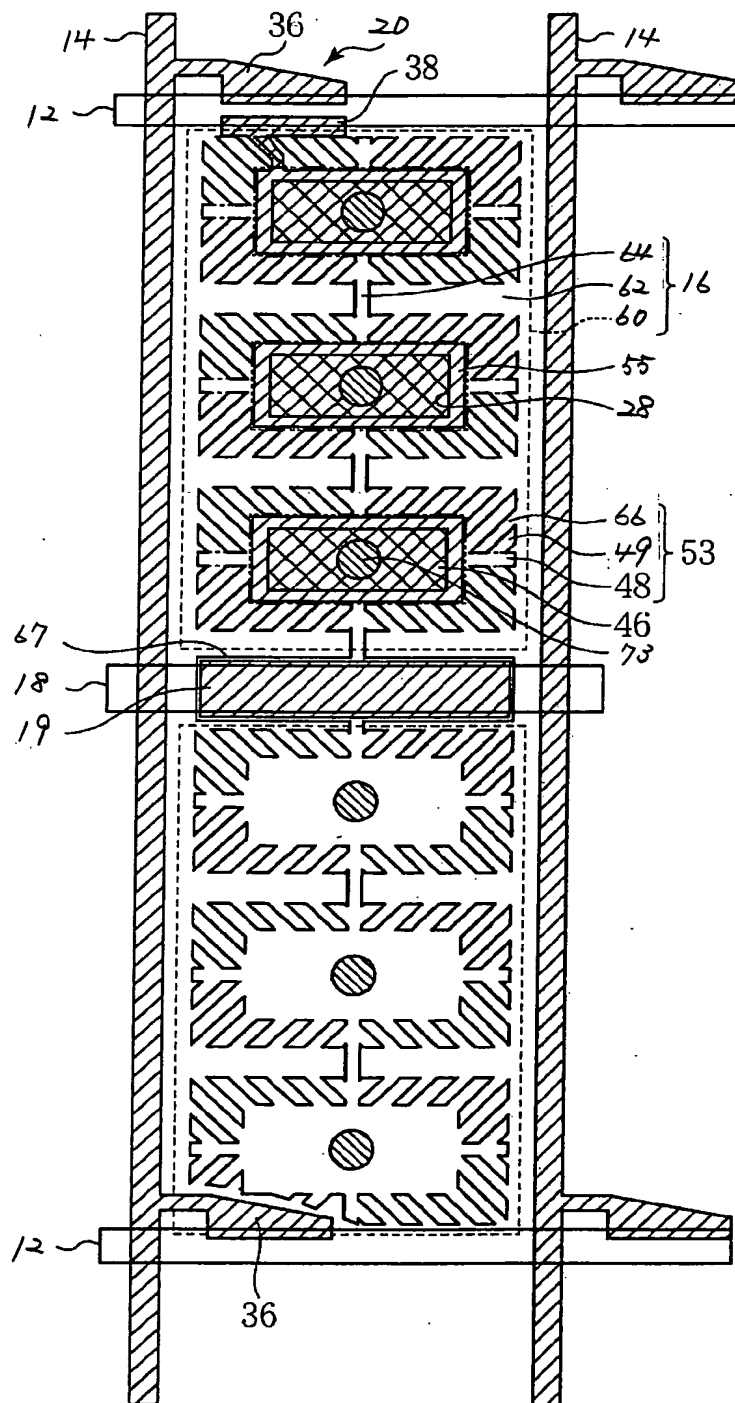
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FIG. 49



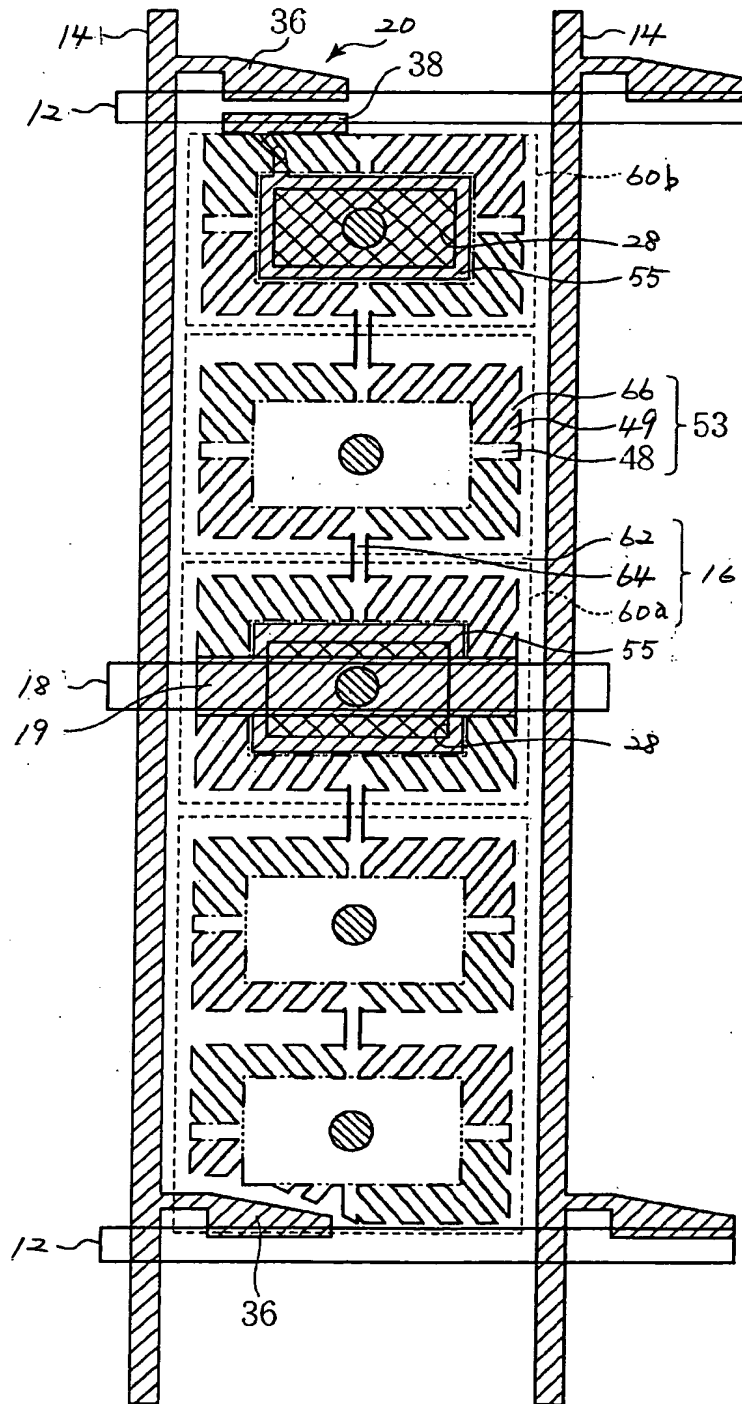
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FIG. 50



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FIG. 51



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FIG.52A

AREAL RATIO OF REFLECTION AREA WHERE
 REFLECTIVITY OF 5% OR MORE IS OBTAINED

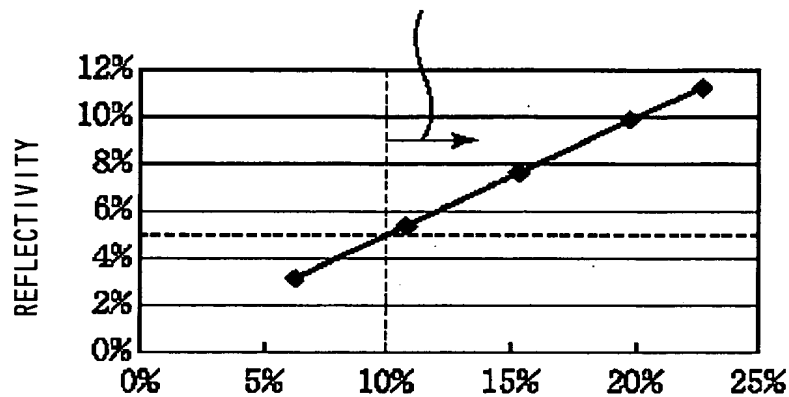
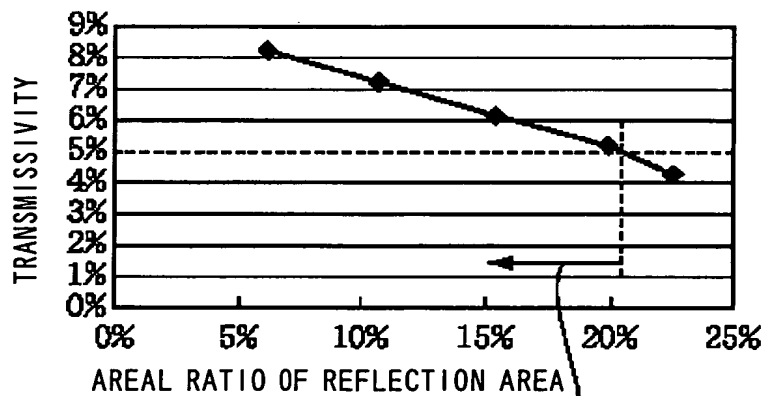


FIG.52B

AREAL RATIO OF REFLECTION AREA



AREAL RATIO OF REFLECTION AREA WHERE
 TRANSMISSIVITY OF 5% OR MORE IS OBTAINED

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FIG.53A

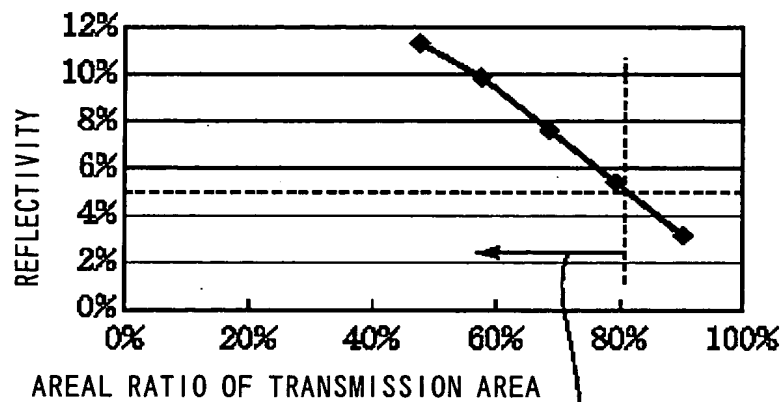
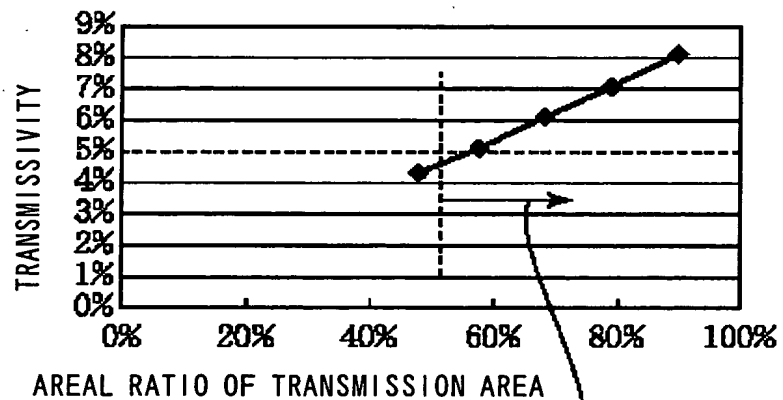


FIG.53B



AREAL RATIO OF TRANSMISSION AREA WHERE
 REFLECTIVITY OF 5% OR MORE IS OBTAINED

AREAL RATIO OF TRANSMISSION AREA WHERE
 TRANSMISSIVITY OF 5% OR MORE IS OBTAINED

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FIG.54A



FIG.54B



FIG.54C

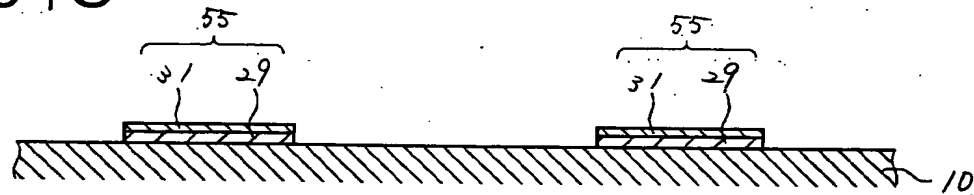
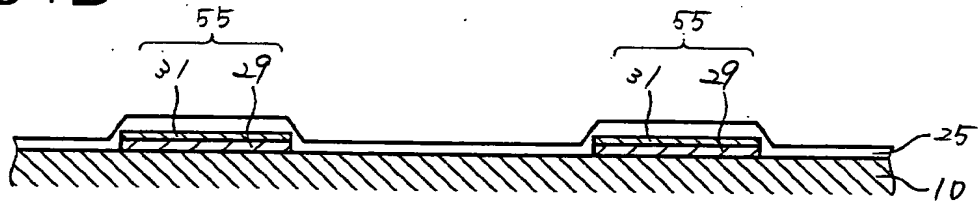


FIG.54D



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FIG.55A

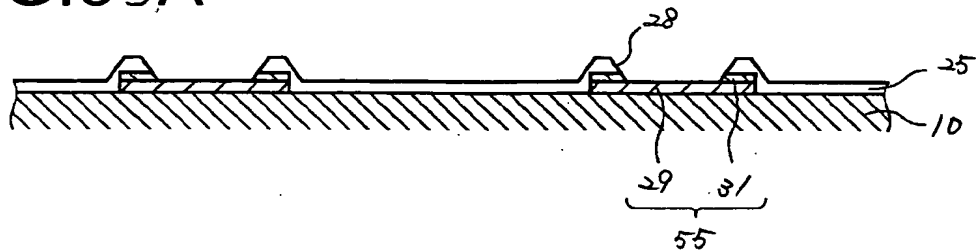


FIG.55B

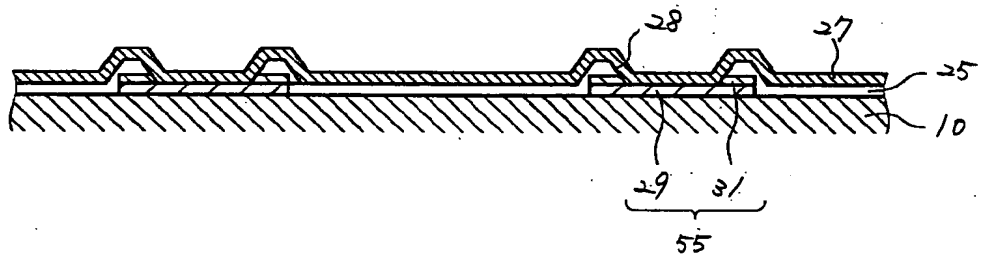
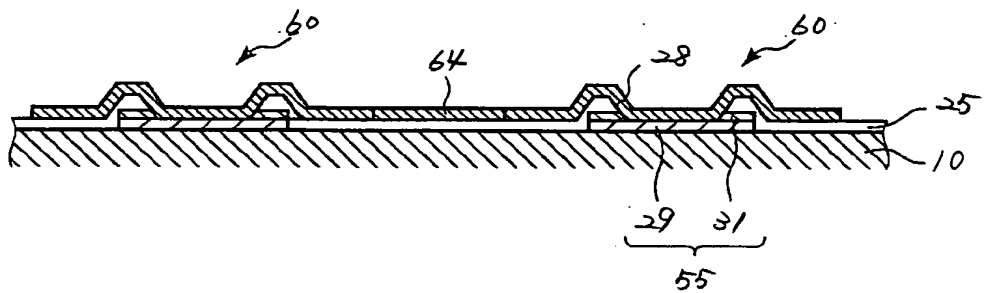
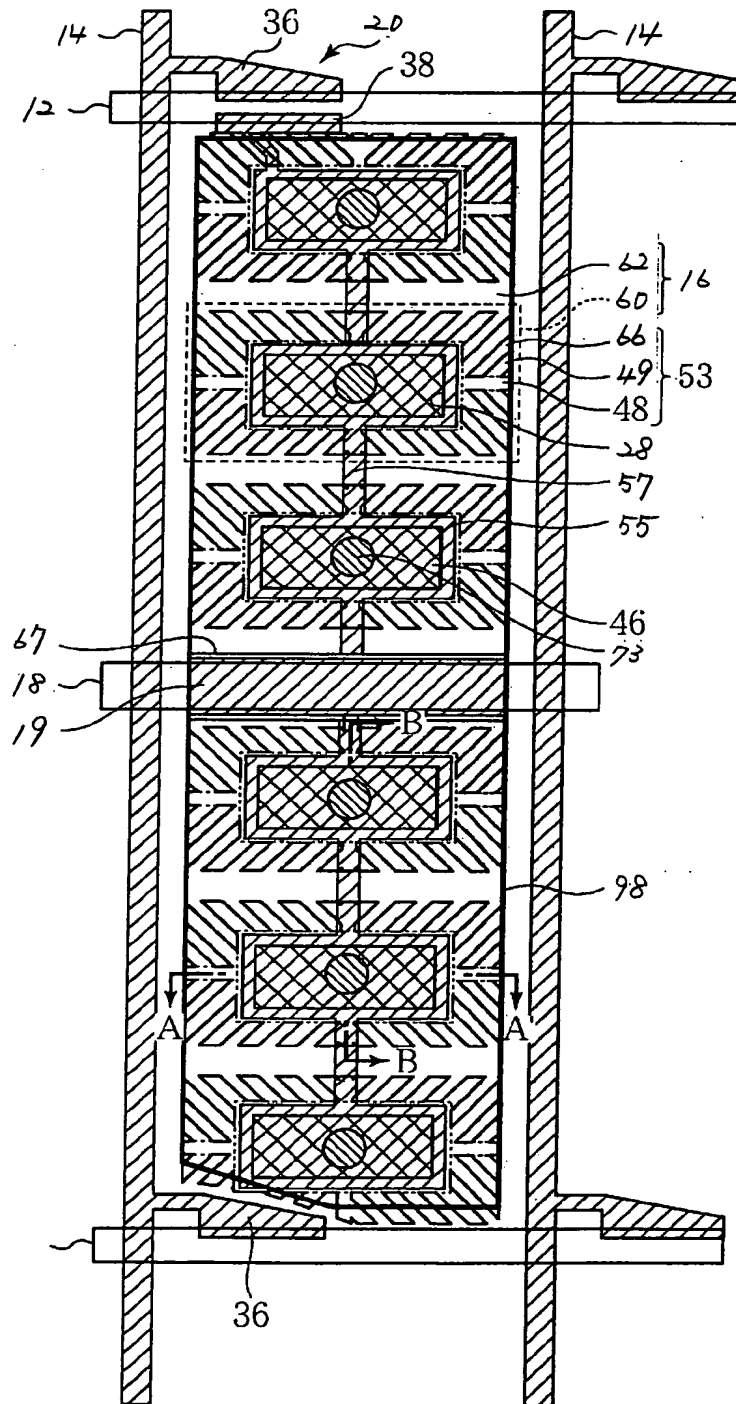


FIG.55C



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FIG. 56



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FIG. 57A

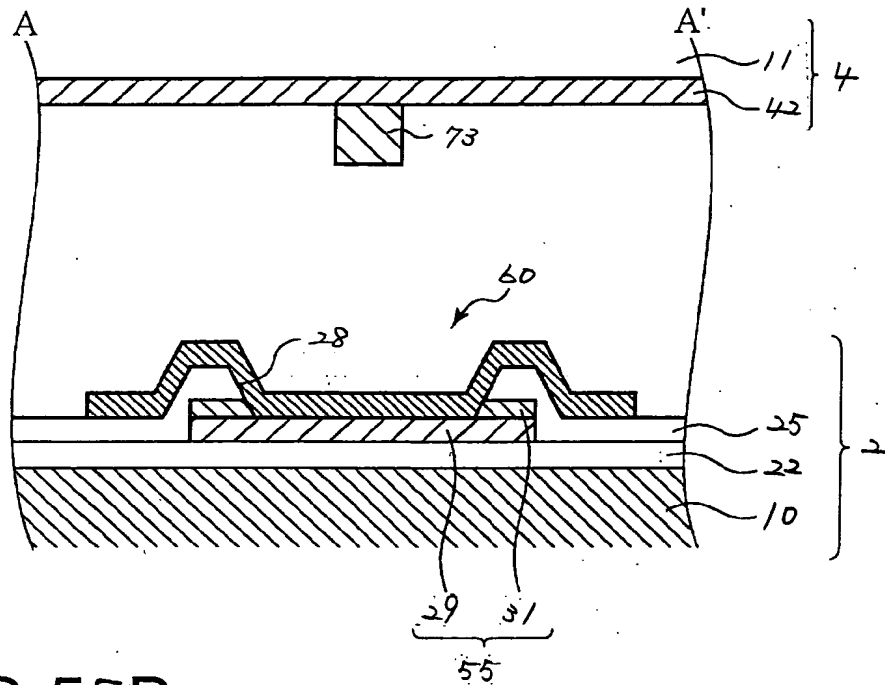
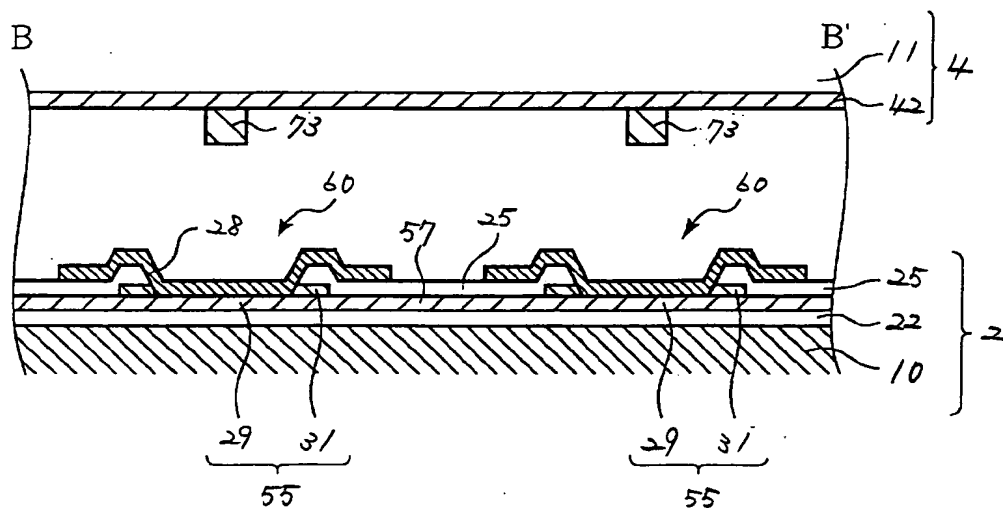


FIG. 57B



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FIG. 60

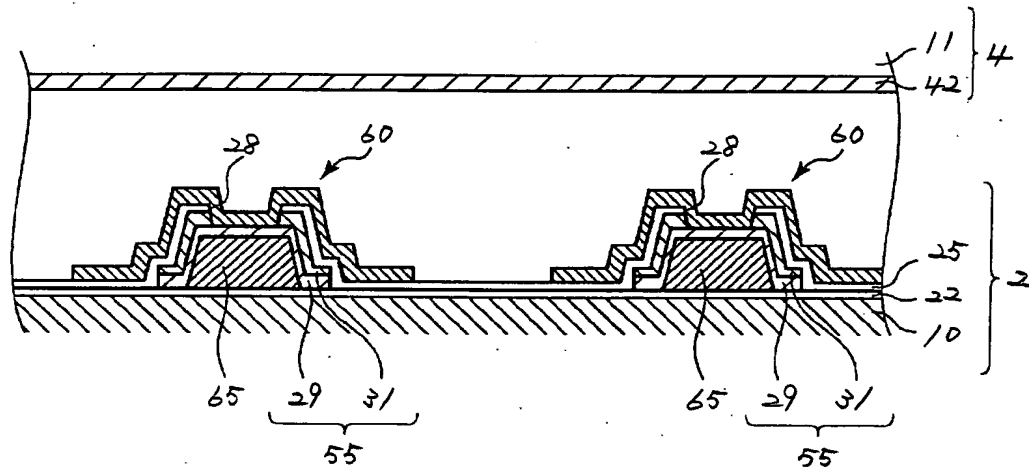


FIG. 61A

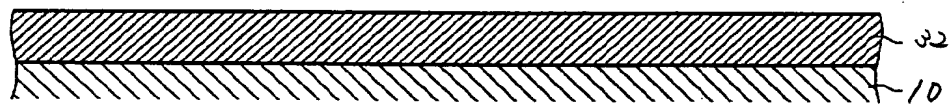


FIG. 61B

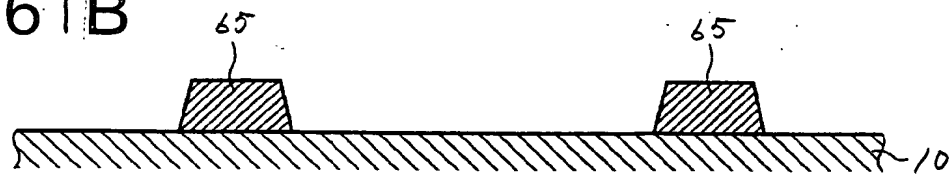
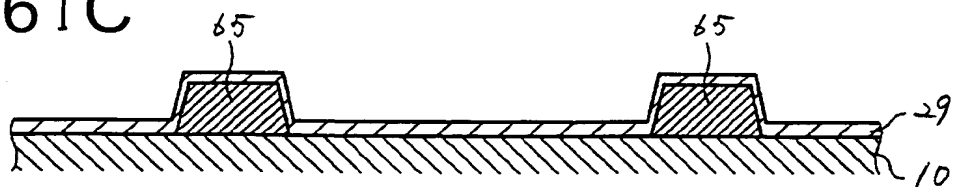


FIG. 61C



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FIG. 62A

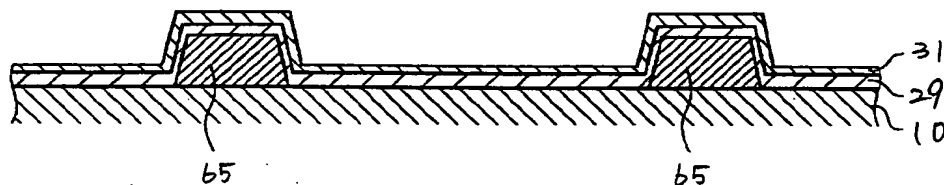


FIG. 62B

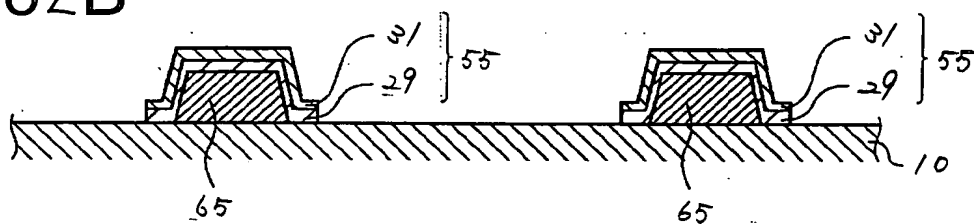
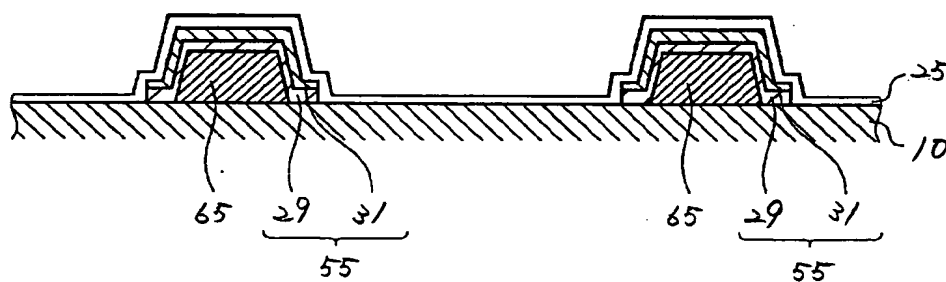


FIG. 62C



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FIG.63A

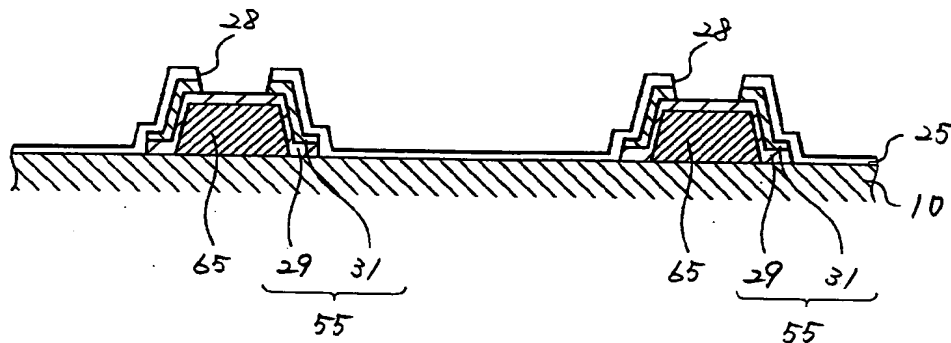


FIG.63B

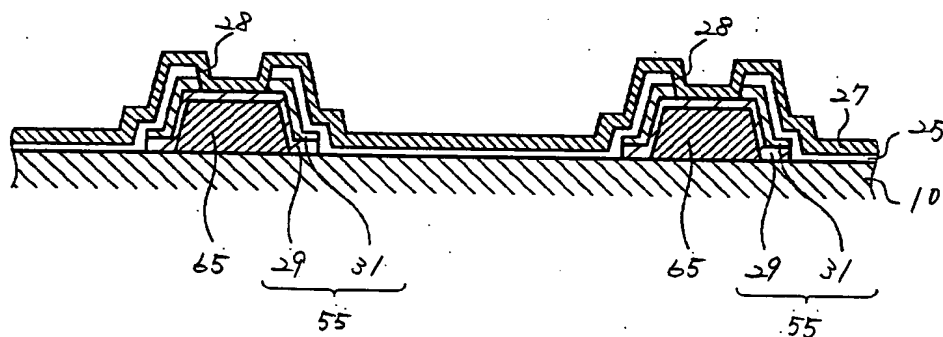
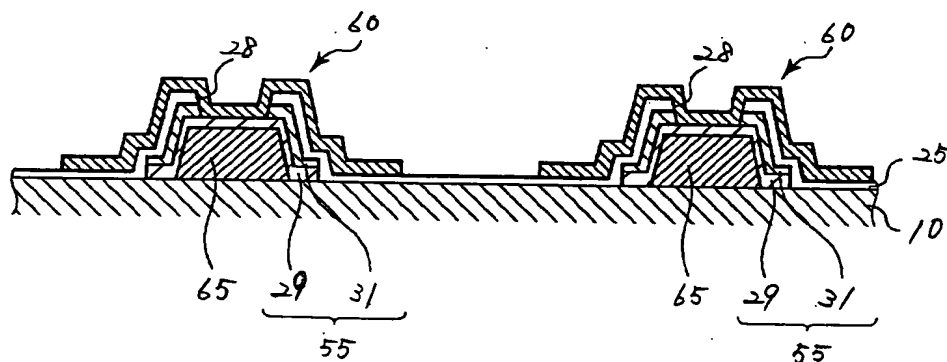
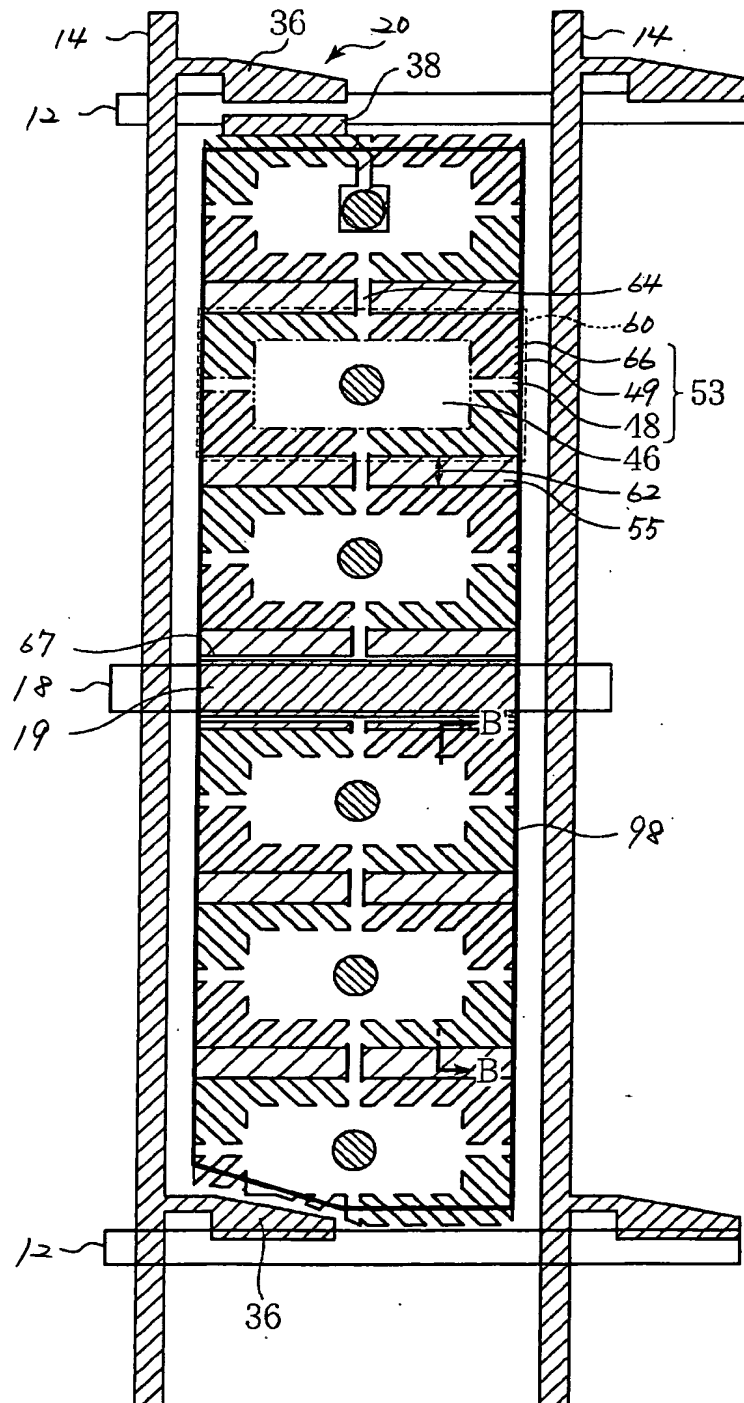


FIG.63C



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FIG. 65



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FIG.66

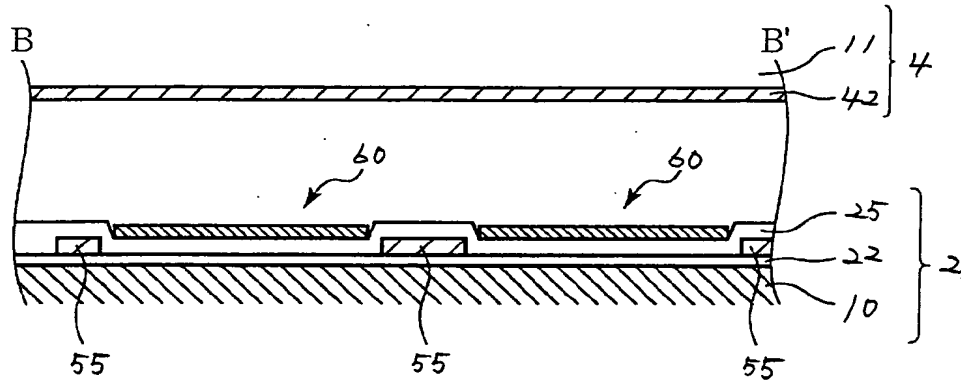


FIG.67A



FIG.67B

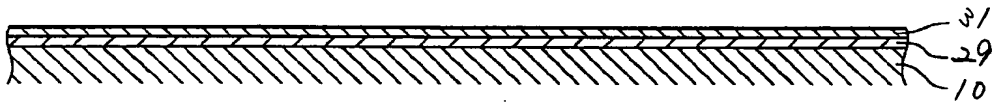


FIG.67C

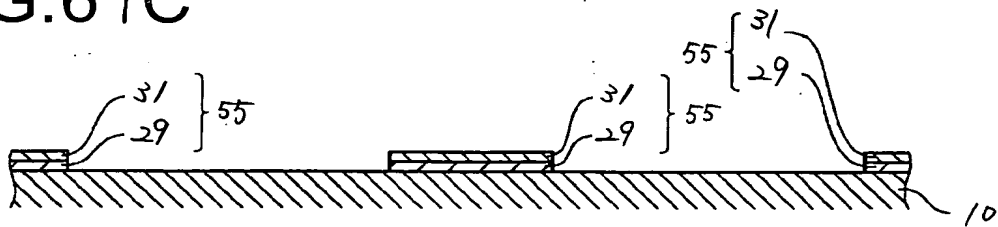
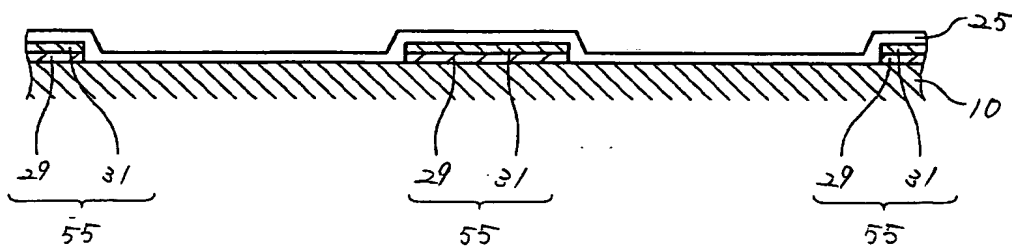


FIG.67D



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FIG. 68A

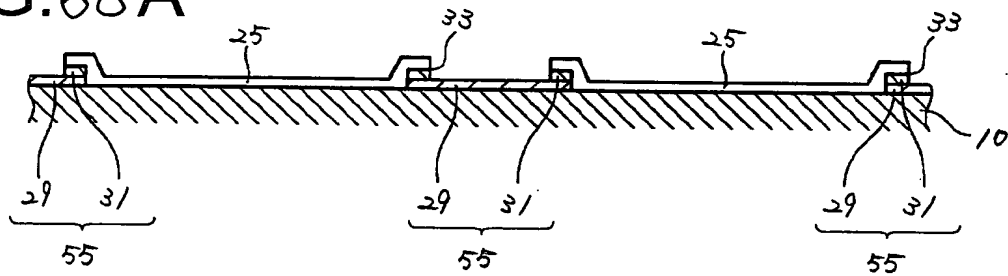


FIG. 68B

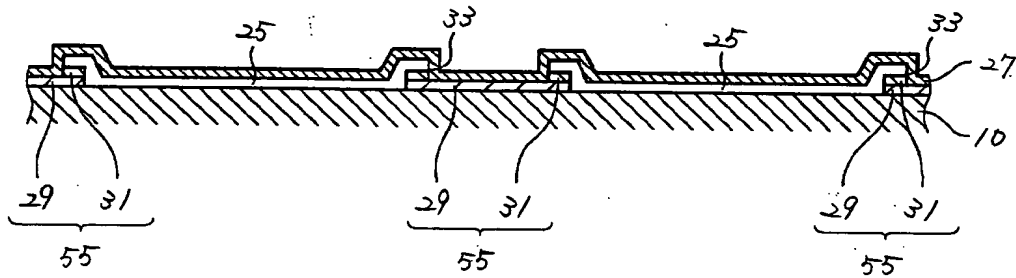
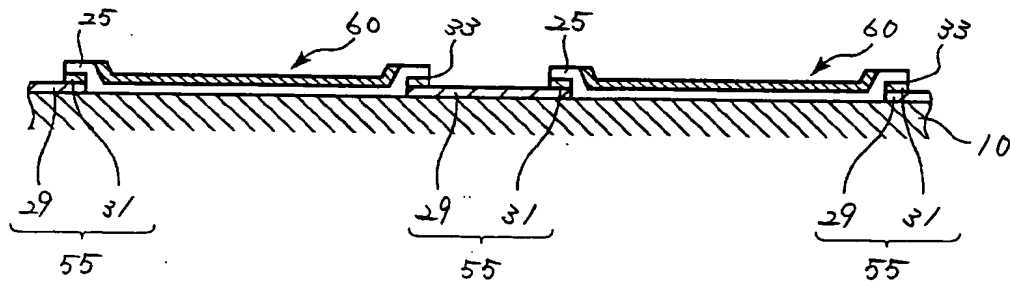
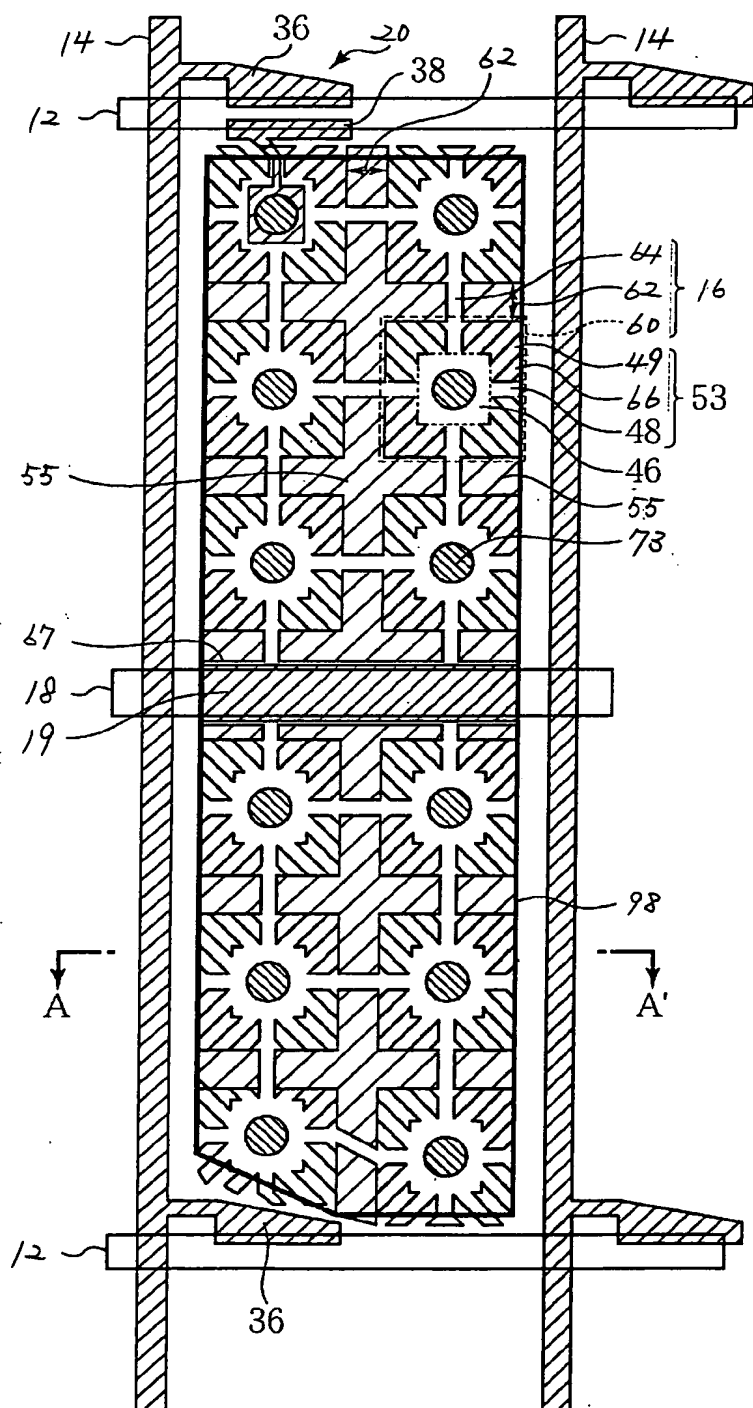


FIG. 68C



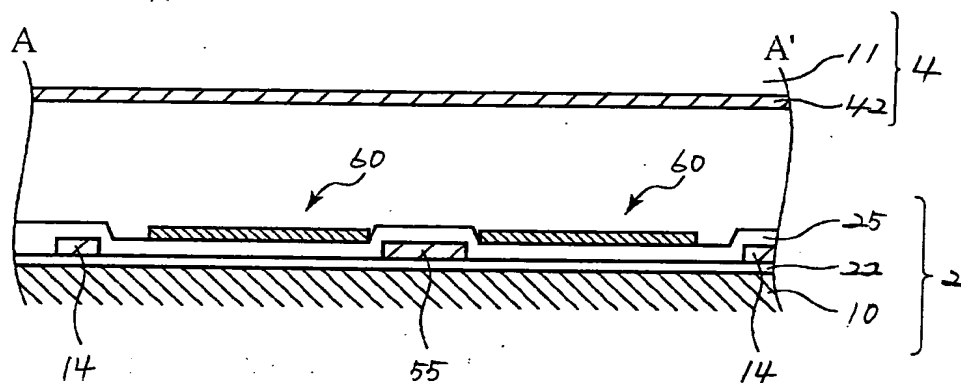
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FIG. 69



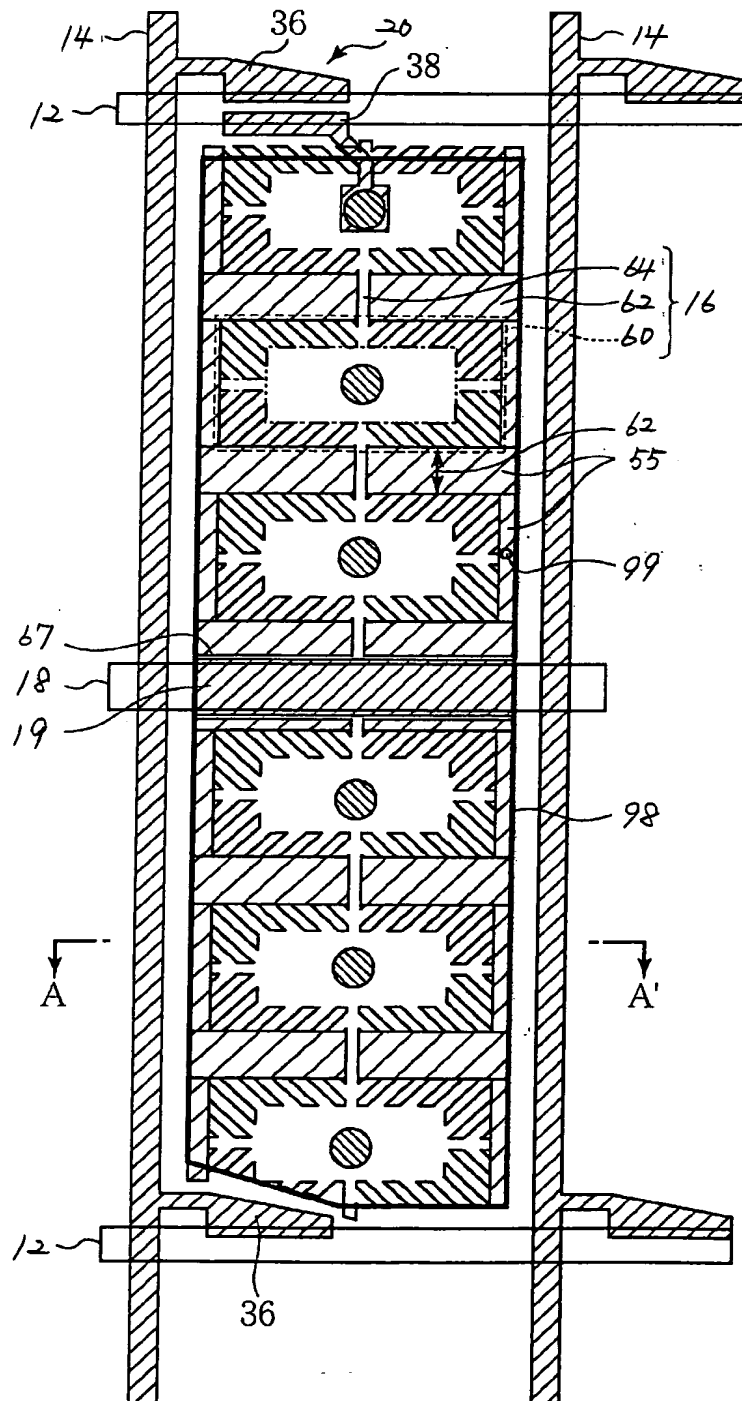
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FIG. 70



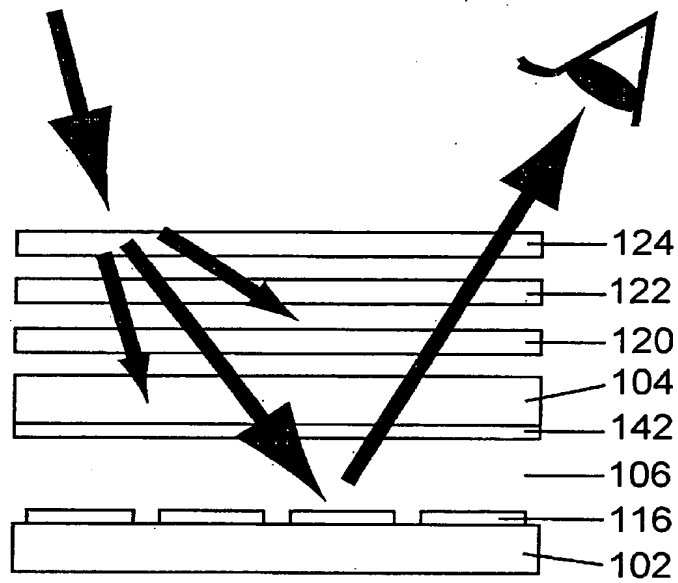
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FIG. 7 1



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FIG. 74



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FIG.75A

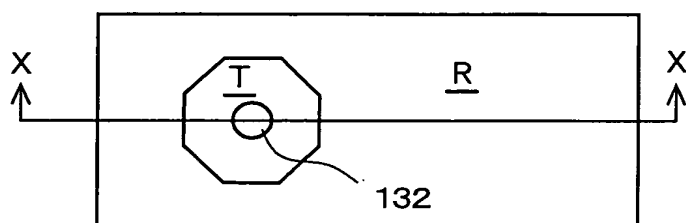
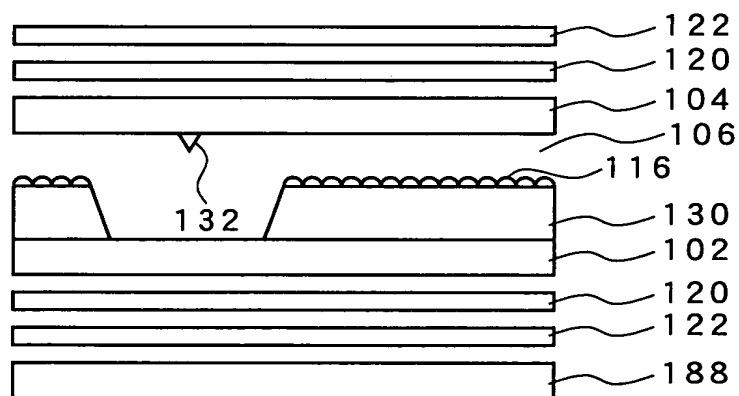


FIG.75B



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FIG.76A

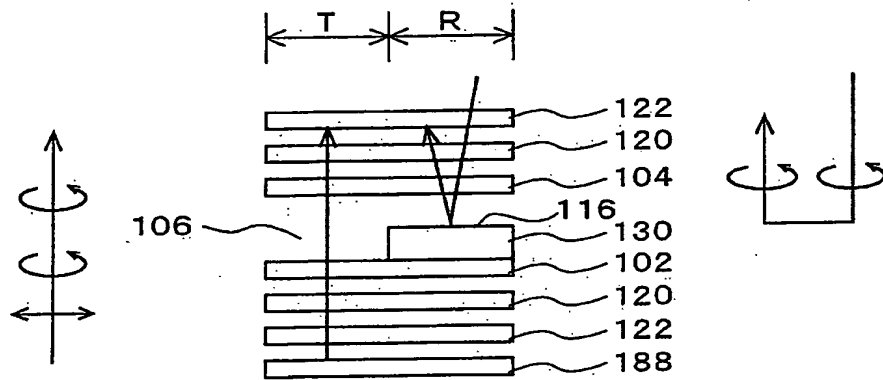


FIG.76B

